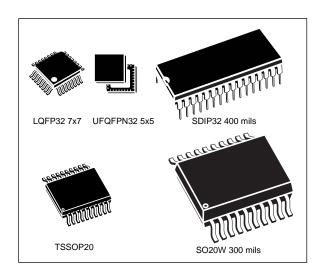


STM8S903K3 STM8S903F3

16 MHz STM8S 8-bit MCU, up to 8 Kbytes Flash, 1 Kbyte RAM, 640 bytes EEPROM,10-bit ADC, 2 timers, UART, SPI, I²C



Features

Core

- 16 MHz advanced STM8 core with Harvard architecture and 3-stage pipeline
- Extended instruction set

Memories

- Program memory: 8 Kbytes Flash; data retention 20 years at 55 °C after 10 kcycles
- Data memory: 640 bytes true data EEPROM; endurance 300 kcycles
- RAM: 1 Kbytes

Clock, reset and supply management

- 2.95 to 5.5 V operating voltage
- Flexible clock control, 4 master clock sources:
 - Low power crystal resonator oscillator
 - External clock input
 - Internal, user-trimmable 16 MHz RC
 - Internal low power 128 kHz RC
- Clock security system with clock monitor
- Power management:
 - Low power modes (wait, active-halt, halt)
 - Switch-off peripheral clocks individually

 Permanently active, low consumption power-on and power-down reset

Interrupt management

- Nested interrupt controller with 32 interrupts
- Up to 28 external interrupts on 7 vectors

Timers

- Advanced control timer: 16-bit, 4 CAPCOM channels, 3 complementary outputs, dead-time insertion and flexible synchronization
- 16-bit general purpose timer, with 3 CAPCOM channels (IC, OC or PWM)
- 8-bit basic timer with 8-bit prescaler
- Auto wake-up timer
- 2 watchdog timers: Window watchdog and independent watchdog

Communications interfaces

- UART with clock output for synchronous operation, Smartcard, IrDA, LIN master mode
- SPI interface up to 8 Mbit/s
- I²C interface up to 400 Kbit/s

Analog to digital converter (ADC)

- 10-bit, ±1 LSB ADC with up to 7 multiplexed channels + 1 internal channel, scan mode and analog watchdog
- Internal reference voltage measurement

I/Os

- Up to 28 I/Os on a 32-pin package including 21 high sink outputs
- Highly robust I/O design, immune against current injection
- Development support
 - Embedded single wire interface module (SWIM) for fast on-chip programming and non intrusive debugging

Unique ID

• 96-bit key including lot number

September 2010 DocID15590 Rev 5 1/113

Contents

1	Introduction	8
2	Description	9
3	Block diagram	10
4	Product overview	11
	4.1 Central processing unit STM8	11
	4.2 Single wire interface module (SWIM) and debug module (DM)	
	4.3 Interrupt controller	12
	4.4 Flash program and data EEPROM memory	12
	4.5 Clock controller	13
	4.6 Power management	14
	4.7 Watchdog timers	14
	4.8 Auto wakeup counter	15
	4.9 Beeper	15
	4.10 TIM1 - 16-bit advanced control timer	15
	4.11 TIM5 - 16-bit general purpose timer	16
	4.12 TIM6 - 8-bit basic timer	
	4.13 Analog-to-digital converter (ADC1)	
	4.14 Communication interfaces	
	4.14.1 UART1	
	4.14.2 SPI	
	4.14.3 I ² C	
5	Pinout and pin description	19
	5.1 STM8S903K3/F3 TSSOP20/SO20 pinout	
	5.2 STM8S903K3/F3 UFQFPN32/LQFP32/SDIP32 pinout	
	5.3 Pin description	
	5.4 Alternate function remapping	
6	Memory and register map	25
	6.1 Memory map	25
	6.2 Register map	
	6.2.1 I/O port hardware register map	26
	6.2.2 General hardware register map	27
	6.2.3 CPU/SWIM/debug module/interrupt controller registers	
7	Interrupt vector mapping	39
8	Option bytes	41
	8.1 STM8S903K3/F3 alternate function remapping bits	43
9	Unique ID	47
	0 Electrical characteristics	

	10.1 Parameter conditions	48
	10.1.1 Minimum and maximum values	48
	10.1.2 Typical values	48
	10.1.3 Typical curves	48
	10.1.4 Loading capacitor	48
	10.1.5 Pin input voltage	49
	10.2 Absolute maximum ratings	49
	10.3 Operating conditions	51
	10.3.1 VCAP external capacitor	52
	10.3.2 Supply current characteristics	53
	10.3.3 External clock sources and timing characteristics	63
	10.3.4 Internal clock sources and timing characteristics	65
	10.3.5 Memory characteristics	67
	10.3.6 I/O port pin characteristics	68
	10.3.7 Reset pin characteristics	76
	10.3.8 SPI serial peripheral interface	79
	10.3.9 I ² C interface characteristics	82
	10.3.10 10-bit ADC characteristics	83
	10.3.11 EMC characteristics	87
11 Pa	ckage information	90
	11.1 32-pin LQFP package mechanical data	90
	11.2 32-lead UFQFPN package mechanical data	92
	11.3 UFQFPN recommended footprint	94
	11.4 SDIP32 package mechanical data	95
	11.5 20-pin TSSOP package mechanical data	97
	11.6 20-pin SO package mechanical data	98
12 Th	nermal characteristics	100
	12.1 Reference document	101
	12.2 Selecting the product temperature range	101
13 Or	dering information	
	13.1 STM8S903K3 FASTROM microcontroller option list	
14 ST	FM8 development tools	
	14.1 Emulation and in-circuit debugging tools	
	14.2 Software tools	
	14.2.1 STM8 toolset	
	14.2.2 C and assembly toolchains	
	14.3 Programming tools	
15 Re	evision history	



List of tables

Table 1. STM8S903K3/F3 access line features	
Table 2. Peripheral clock gating bit assignments in CLK_PCKENR1/2 registers	14
Table 3. TIM timer features	
Table 4. Legend/abbreviations for pinout tables	
Table 5. TSSOP20/SO20/UFQFPN32/LQFP32/SDIP32 pin description	22
Table 6. I/O port hardware register map	
Table 7. General hardware register map	
Table 8. CPU/SWIM/debug module/interrupt controller registers	
Table 9. Interrupt mapping	
Table 10. Option bytes	
Table 11. Option byte description	
Table 12. STM8S903K3 alternate function remapping bits [7:2] for 32-pin packages	
Table 13. STM8S903F3 alternate function remapping bits [7:2] for 20-pin packages	
Table 14. STM8S903K3 alternate function remapping bits [1:0] for 32-pin packages	
Table 15. STM8S903F3 alternate function remapping bits [1:0] for 20-pin packages	
Table 16. Unique ID registers (96 bits)	
Table 17. Voltage characteristics	
Table 18. Current characteristics	
Table 19. Thermal characteristics	
Table 20. General operating conditions	
Table 21. Operating conditions at power-up/power-down	
Table 22. Total current consumption with code execution in run mode at V_{DD} = 5 V	53
Table 23. Total current consumption with code execution in run mode at V _{DD} = 3.3 V	54
Table 24. Total current consumption in wait mode at V _{DD} = 5 V	
Table 25. Total current consumption in wait mode at V _{DD} = 3.3 V	
Table 26. Total current consumption in active halt mode at V_{DD} = 5 V	
Table 27. Total current consumption in active halt mode at V _{DD} = 3.3 V	
Table 28. Total current consumption in halt mode at V _{DD} = 5 V	
Table 29. Total current consumption in halt mode at V _{DD} = 3.3 V	
Table 30. Wakeup times	
Table 31. Total current consumption and timing in forced reset state	
Table 32. Peripheral current consumption	
Table 33. HSE user external clock characteristics	
Table 34. HSE oscillator characteristics	
Table 35. HSI oscillator characteristics	
Table 36. LSI oscillator characteristics	
Table 37. RAM and hardware registers	
Table 38. Flash program memory/data EEPROM memory	67
Table 39. I/O static characteristics	
Table 40. Output driving current (standard ports)	
Table 41. Output driving current (true open drain ports)	
Table 42. Output driving current (high sink ports)	
Table 43. NRST pin characteristics	
Table 44. SPI characteristics	
Table 45. I ² C characteristics	
Table 46. ADC characteristics	
Table 47. ADC accuracy with R_{AIN} < 10 k Ω , V_{DD} = 5 V	84



Table 48. ADC accuracy with R _{AIN} < 10 kΩ R _{AIN} , V _{DD} = 3.3 V	85
Table 49. EMS data	
Table 50. EMI data	88
Table 51. ESD absolute maximum ratings	89
Table 52. Electrical sensitivities	
Table 53. 32-pin low profile quad flat package mechanical data	100
Table 54. 32-lead, ultra thin, fine pitch quad flat no-lead package mechanical data	
Table 55. 32-lead shrink plastic DIP (400 ml) package mechanical data	96
Table 56. 20-pin, 4.40 mm body, 0.65 mm pitch mechanical data	98
Table 57. 20-lead, plastic small outline (300 mils) mechanical data	98
Table 58. Thermal characteristics	100
Table 59. Document revision history	110

577

List of figures

Figure 1. E	Block diagram	.10
Figure 2. F	Flash memory organization	.13
	STM8S903K3/F3 TSSOP20/SO20 pinout	
	STM8S903K3/F3 UFQFPN32/LQFP32 pinout	
	STM8S903K3/F3 SDIP32 pinout	
	Memory map	
	Pin loading conditions	
	Pin input voltage	
	CPUmax versus V _{DD}	
	External capacitor C _{EXT}	
Figure 11.	Typ I _{DD(RUN)} vs. V _{DD} HSE user external clock, f _{CPU} = 16 MHz	.60
Figure 12.	Typ $I_{DD(RUN)}$ vs. f_{CPU} HSE user external clock, V_{DD} = 5 V	.61
Figure 13.	Typ $I_{DD(RUN)}$ vs. V_{DD} HSI RC osc, f_{CPU} = 16 MHz	.61
Figure 14.	Typ I _{DD(WFI)} vs. V _{DD} HSE user external clock, f _{CPU} = 16 MHz	.62
Figure 15	Typ $I_{DD(WFI)}$ vs. f_{CPU} HSE user external clock, $V_{DD} = 5 \text{ V}$	62
	Typ I _{DD(WFI)} vs. V _{DD} HSI RC osc, f _{CPU} = 16 MHz	
	HSE external clocksource	
	HSE oscillator circuit diagram	
	Typical HSI accuracy at V _{DD} = 5 V vs 5 temperatures	
	Typical HSI frequency variation vs V _{DD} @ 4 temperatures	
	Typical LSI frequency variation vs V _{DD} @ 4 temperatures	
	Typical V _{IL} and V _{IH} vs V _{DD} @ 4 temperatures	
	Typical pull-up resistance vs V _{DD} @ 4 temperatures	
	Typical pull-up current vs V _{DD} @ 4 temperatures	
	Typ. V_{OL} @ V_{DD} = 5 V (standard ports)	
	Typ. $V_{OL} @ V_{DD} = 3.3 \text{ V (standard ports)}$	
	Typ. V_{OL} @ V_{DD} = 5.5 V (standard ports)	
	Typ. V_{OL} @ V_{DD} = 3.3 V (true open drain ports)	
	Typ. V _{OL} @ V _{DD} = 5 V (high sink ports)	
	Typ. V_{OL} @ V_{DD} = 3.3 V (high sink ports)	
	Typ. $V_{DD} - V_{OH} @ V_{DD} = 5 V$ (standard ports)	
	Typ. $V_{DD} - V_{OH} @ V_{DD} = 3.3 \text{ V (standard ports)}$	
	Typ. $V_{DD} - V_{OH} \otimes V_{DD} = 5 \text{ V (high sink ports)}$	
	Typ. $V_{DD} - V_{OH} \otimes V_{DD} = 3.3 \text{ V (high sink ports)}$	
	Typical NRST V _{IL} and V _{IH} vs V _{DD} @ 4 temperatures	
	Typical NRST pull-up resistance vs V _{DD} @ 4 temperatures	
	Typical NRST pull-up current vs V _{DD} @ 4 temperatures	
	Recommended reset pin protection	
	SPI timing diagram - slave mode and CPHA = 0	
rigure 40.	SPI timing diagram - slave mode and CPHA = 1	
rigure 41.	SPI timing diagram - master mode ⁽¹⁾	
	Typical application with I ² C bus and timing diagram	
_	ADC accuracy characteristics	
	Typical application with ADC	
	32-pin low profile quad flat package (7 x 7)	
	32-lead, ultra thin, fine pitch quad flat no-lead package (5 x 5)	
FIGURE 47	Recommended toothrint for on-hoard emiliation	94



STM8S903K3 STM8S903F3

List of figures

Figure 48. Recommended footprint without on-board emulation	95
Figure 49. 32-lead shrink plastic DIP (400 ml) package	
Figure 50. 20-pin, 4.40 mm body, 0.65 mm pitch	
Figure 51. 20-lead, plastic small outline (300 mils) package	
Figure 52. STM8S903K3 ordering information scheme	

4

1 Introduction

This datasheet contains the description of the device features, pinout, electrical characteristics, mechanical data and ordering information.

- For complete information on the STM8S microcontroller memory, registers and peripherals, please refer to the STM8S microcontroller family reference manual (RM0016).
- For information on programming, erasing and protection of the internal Flash memory please refer to the STM8S Flash programming manual (PM0051).
- For information on the debug and SWIM (single wire interface module) refer to the STM8 SWIM communication protocol and debug module user manual (UM0470).
- For information on the STM8 core, please refer to the STM8 CPU programming manual (PM0044).

2 Description

The STM8S903K3 and STM8S903F3 8-bit microcontrollers offer 8 Kbytes Flash program memory, plus integrated true data EEPROM. The STM8S microcontroller family reference manual (RM0016) refers to devices in this family as low-density. They provide the following benefits:

- Reduced system cost
 - Integrated true data EEPROM for up to 300 k write/erase cycles
 - High system integration level with internal clock oscillators, watchdog and brown-out reset.
- Performance and robustness
 - 16 MHz CPU clock frequency
 - Robust I/O, independent watchdogs with separate clock source
 - Clock security system
- Full documentation and a wide choice of development tools
- Advanced core and peripherals made in a state-of-the art technology

Table 1: STM8S903K3/F3 access line features

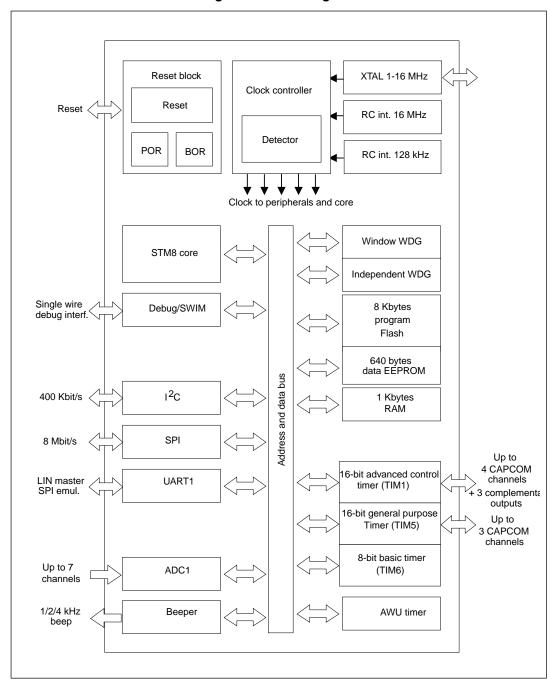
Device	STM8S903K3/F3
Pin count	32
Max. number of GPIOs (I/Os)	28 ⁽¹⁾
Ext. interrupt pins	28
Timer CAPCOM channels	7
Timer complementary outputs	3
A/D converter channels	7
High sink I/Os	21
Low density Flash program memory(bytes)	8K
Data EEPROM (bytes)	640 ⁽²⁾
RAM (bytes)	1K
Peripheral set	Multipurpose timer (TIM1), SPI, I ² C, UART window WDG, independent WDG, ADC, PWM timer (TIM5), 8-bit timer (TIM6)

⁽¹⁾ Including 21 high sink outputs

⁽²⁾ No read-while-write (RWW) capability

3 Block diagram

Figure 1: Block diagram



4 Product overview

The following section intends to give an overview of the basic features of the device functional modules and peripherals.

For more detailed information please refer to the corresponding family reference manual (RM0016).

4.1 Central processing unit STM8

The 8-bit STM8 core is designed for code efficiency and performance.

It contains 6 internal registers which are directly addressable in each execution context, 20 addressing modes including indexed indirect and relative addressing and 80 instructions.

Architecture and registers

- Harvard architecture
- 3-stage pipeline
- 32-bit wide program memory bus single cycle fetching for most instructions
- X and Y 16-bit index registers enabling indexed addressing modes with or without offset and read-modify-write type data manipulations
- 8-bit accumulator
- 24-bit program counter 16-Mbyte linear memory space
- 16-bit stack pointer access to a 64 K-level stack
- 8-bit condition code register 7 condition flags for the result of the last instruction

Addressing

- 20 addressing modes
- Indexed indirect addressing mode for look-up tables located anywhere in the address space
- Stack pointer relative addressing mode for local variables and parameter passing

Instruction set

- 80 instructions with 2-byte average instruction size
- Standard data movement and logic/arithmetic functions
- 8-bit by 8-bit multiplication
- 16-bit by 8-bit and 16-bit by 16-bit division
- Bit manipulation
- Data transfer between stack and accumulator (push/pop) with direct stack access
- Data transfer using the X and Y registers or direct memory-to-memory transfers

4.2 Single wire interface module (SWIM) and debug module (DM)

The single wire interface module and debug module permits non-intrusive, real-time in-circuit debugging and fast memory programming.

SWIM

Single wire interface module for direct access to the debug module and memory programming. The interface can be activated in all device operation modes. The maximum data transmission speed is 145 bytes/ms.

Debug module

The non-intrusive debugging module features a performance close to a full-featured emulator. Beside memory and peripherals, also CPU operation can be monitored in real-time by means of shadow registers.

- R/W to RAM and peripheral registers in real-time
- R/W access to all resources by stalling the CPU
- Breakpoints on all program-memory instructions (software breakpoints)
- Two advanced breakpoints, 23 predefined configurations

4.3 Interrupt controller

- Nested interrupts with three software priority levels
- 32 interrupt vectors with hardware priority
- Up to 28 external interrupts on 7 vectors including TLI
- Trap and reset interrupts

4.4 Flash program and data EEPROM memory

- 8 Kbytes of Flash program single voltage Flash memory
- 640 bytes true data EEPROM
- User option byte area

Write protection (WP)

Write protection of Flash program memory and data EEPROM is provided to avoid unintentional overwriting of memory that could result from a user software malfunction.

There are two levels of write protection. The first level is known as MASS (memory access security system). MASS is always enabled and protects the main Flash program memory, data EEPROM and option bytes.

To perform in-application programming (IAP), this write protection can be removed by writing a MASS key sequence in a control register. This allows the application to write to data EEPROM, modify the contents of main program memory or the device option bytes.

A second level of write protection, can be enabled to further protect a specific area of memory known as UBC (user boot code). Refer to the figure below.

The size of the UBC is programmable through the UBC option byte, in increments of 1 page (64-byte block) by programming the UBC option byte in ICP mode.

This divides the program memory into two areas:

- Main program memory: Up to 8 Kbytes minus UBC
- User-specific boot code (UBC): Configurable up to 8 Kbytes

The UBC area remains write-protected during in-application programming. This means that the MASS keys do not unlock the UBC area. It protects the memory used to store the boot



program, specific code libraries, reset and interrupt vectors, the reset routine and usually the IAP and communication routines.

Data memory area (640 bytes) Data EEPROM memory Option bytes Programmable area from 64 **UBC** area bytes(1 page) Remains write protected during IAP up to 8 Kbytes (in 1 page steps) Low density Flash program memory (8 Kbytes) Program memory area Write access possible for IAP

Figure 2: Flash memory organization

Read-out protection (ROP)

The read-out protection blocks reading and writing the Flash program memory and data EEPROM memory in ICP mode (and debug mode). Once the read-out protection is activated, any attempt to toggle its status triggers a global erase of the program and data memory. Even if no protection can be considered as totally unbreakable, the feature provides a very high level of protection for a general purpose microcontroller.

4.5 Clock controller

The clock controller distributes the system clock (f_{MASTER}) coming from different oscillators to the core and the peripherals. It also manages clock gating for low power modes and ensures clock robustness.

Features

- Clock prescaler: To get the best compromise between speed and current consumption the clock frequency to the CPU and peripherals can be adjusted by a programmable prescaler.
- Safe clock switching: Clock sources can be changed safely on the fly in run mode through a configuration register. The clock signal is not switched until the new clock source is ready. The design guarantees glitch-free switching.
- Clock management: To reduce power consumption, the clock controller can stop the clock to the core, individual peripherals or memory.
- Master clock sources: Four different clock sources can be used to drive the master clock:
 - 1-16 MHz high-speed external crystal (HSE)

- Up to 16 MHz high-speed user-external clock (HSE user-ext)
- 16 MHz high-speed internal RC oscillator (HSI)
- 128 kHz low-speed internal RC (LSI)
- Startup clock: After reset, the microcontroller restarts by default with an internal 2 MHz clock (HSI/8). The prescaler ratio and clock source can be changed by the application program as soon as the code execution starts.
- Clock security system (CSS): This feature can be enabled by software. If an HSE clock failure occurs, the internal RC (16 MHz/8) is automatically selected by the CSS and an interrupt can optionally be generated.
- Configurable main clock output (CCO): This outputs an external clock for use by the application.

Bit	Peripheral Bit clock		Peripheral clock	Bit	Peripheral clock	Bit	Peripheral clock				
PCKEN17	TIM1	PCKEN13	UART1	PCKEN27	Reserved	CKEN23	ADC				
PCKEN16	IM5	PCKEN12	Reserved	PCKEN26	Reserved	PCKEN22	AWU				
PCKEN15	Reserved	PCKEN11	SPI	PCKEN25	Reserved	PCKEN21	Reserved				
PCKEN14	TIM6	PCKEN10	I ² C	PCKEN24	Reserved	PCKEN20	Reserved				

Table 2: Peripheral clock gating bit assignments in CLK_PCKENR1/2 registers

4.6 Power management

For efficient power management, the application can be put in one of four different low-power modes. You can configure each mode to obtain the best compromise between lowest power consumption, fastest start-up time and available wakeup sources.

- Wait mode: In this mode, the CPU is stopped, but peripherals are kept running. The wakeup is performed by an internal or external interrupt or reset.
- Active halt mode with regulator on: In this mode, the CPU and peripheral clocks are stopped. An internal wakeup is generated at programmable intervals by the auto wake up unit (AWU). The main voltage regulator is kept powered on, so current consumption is higher than in active halt mode with regulator off, but the wakeup time is faster. Wakeup is triggered by the internal AWU interrupt, external interrupt or reset.
- Active halt mode with regulator off: This mode is the same as active halt with regulator on, except that the main voltage regulator is powered off, so the wake up time is slower.
- Halt mode: In this mode the microcontroller uses the least power. The CPU and peripheral
 clocks are stopped, the main voltage regulator is powered off. Wakeup is triggered by
 external event or reset.

4.7 Watchdog timers

The watchdog system is based on two independent timers providing maximum security to the applications.



Activation of the watchdog timers is controlled by option bytes or by software. Once activated, the watchdogs cannot be disabled by the user program without performing a reset.

Window watchdog timer

The window watchdog is used to detect the occurrence of a software fault, usually generated by external interferences or by unexpected logical conditions, which cause the application program to abandon its normal sequence.

The window function can be used to trim the watchdog behavior to match the application perfectly.

The application software must refresh the counter before time-out and during a limited time window.

A reset is generated in two situations:

- 1. Timeout: At 16 MHz CPU clock the time-out period can be adjusted between 75 μs up to 64 ms.
- **2.** Refresh out of window: The downcounter is refreshed before its value is lower than the one stored in the window register.

Independent watchdog timer

The independent watchdog peripheral can be used to resolve processor malfunctions due to hardware or software failures.

It is clocked by the 128 kHZ LSI internal RC clock source, and thus stays active even in case of a CPU clock failure

The IWDG time base spans from 60 µs to 1 s.

4.8 Auto wakeup counter

- Used for auto wakeup from active halt mode
- Clock source: Internal 128 kHz internal low frequency RC oscillator or external clock
- LSI clock can be internally connected to TIM1 input capture channel 1 for calibration

4.9 Beeper

The beeper function outputs a signal on the BEEP pin for sound generation. The signal is in the range of 1, 2 or 4 kHz.

The beeper output port is only available through the alternate function remap option bit AFR7.

4.10 TIM1 - 16-bit advanced control timer

This is a high-end timer designed for a wide range of control applications. With its complementary outputs, dead-time control and center-aligned PWM capability, the field of applications is extended to motor control, lighting and half-bridge driver

- 16-bit up, down and up/down autoreload counter with 16-bit prescaler
- Four independent capture/compare channels (CAPCOM) configurable as input capture, output compare, PWM generation (edge and center aligned mode) and single pulse mode output

- Synchronization module to control the timer with external signals or to synchronise with TIM5 or TIM6
- Break input to force the timer outputs into a defined state
- Three complementary outputs with adjustable dead time
- Encoder mode
- Interrupt sources: 3 x input capture/output compare, 1 x overflow/update, 1 x break

4.11 TIM5 - 16-bit general purpose timer

- 16-bit autoreload (AR) up-counter
- 15-bit prescaler adjustable to fixed power of 2 ratios 1...32768
- 3 individually configurable capture/compare channels
- PWM mode
- Interrupt sources: 3 x input capture/output compare, 1 x overflow/update
- Synchronization module to control the timer with external signals or to synchronize with TIM1 or TIM6

4.12 TIM6 - 8-bit basic timer

- 8-bit autoreload, adjustable prescaler ratio to any power of 2 from 1 to 128
- Clock source: CPU clock
- Interrupt source: 1 x overflow/update
- Synchronization module to control the timer with external signals or to synchronize with TIM1 or TIM5.

Timer	Counter size (bits)	size			Complementary outputs		Timer synchronization/ chaining
TIM1	16	Any integer from 1 to 65536	Up/down	4	3	Yes	Yes
TIM5	16	Any power of 2 from 1 to 32768	Up	3	0	No	
TIM6	8	Any power of 2 from 1 to 128	Up	0	0	No	

Table 3: TIM timer features

4.13 Analog-to-digital converter (ADC1)

The STM8S903K3 family products contain a 10-bit successive approximation A/D converter (ADC1) with up to 7 external and 1 internal multiplexed input channels and the following main features:

Input voltage range: 0 to V_{DD}

- Conversion time: 14 clock cycles
- Single and continuous and buffered continuous conversion modes
- Buffer size (n x 10 bits) where n = number of input channels
- Scan mode for single and continuous conversion of a sequence of channels
- Analog watchdog capability with programmable upper and lower thresholds
- Internal reference voltage on channel AIN7
- Analog watchdog interrupt
- External trigger input
- Trigger from TIM1 TRGO
- End of conversion (EOC) interrupt

Internal reference voltage

Channel AIN7 is internally connected to the internal reference voltage. This internal reference is constant and can be used, for example, to monitor V_{DD} . It is independent of variations in V_{DD} and ambient temperature T_A .

4.14 Communication interfaces

The following communication interfaces are implemented:

- UART1: Full feature UART, synchronous mode, SPI master mode, Smartcard mode, IrDA mode, single wire mode, LIN2.1 master capability
- SPI: Full and half-duplex, 8 Mbit/s
- I²C: Up to 400 Kbit/s

4.14.1 UART1

Main features

- One Mbit/s full duplex SCI
- SPI emulation
- High precision baud rate generator
- Smartcard emulation
- IrDA SIR encoder decoder
- LIN master mode
- Single wire half duplex mode

Asynchronous communication (UART mode)

- Full duplex communication NRZ standard format (mark/space)
- Programmable transmit and receive baud rates up to 1 Mbit/s (f_{CPU}/16) and capable of following any standard baud rate regardless of the input frequency
- Separate enable bits for transmitter and receiver
- Two receiver wakeup modes:
 - Address bit (MSB)
 - Idle line (interrupt)

- Transmission error detection with interrupt generation
- Parity control

Synchronous communication

- Full duplex synchronous transfers
- SPI master operation
- 8-bit data communication
- Maximum speed: 1 Mbit/s at 16 MHz (f_{CPU}/16)

LIN master mode

- Emission: Generates 13-bit synch break frame
- Reception: Detects 11-bit break frame

4.14.2 SPI

- Maximum speed: 8 Mbit/s (f_{MASTER}/2) both for master and slave
- Full duplex synchronous transfers
- Simplex synchronous transfers on two lines with a possible bidirectional data line
- Master or slave operation selectable by hardware or software
- CRC calculation
- 1 byte Tx and Rx buffer
- Slave/master selection input pin

4.14.3 I²C

- I2C master features:
 - Clock generation
 - Start and stop generation
- I2C slave features:
 - Programmable I2C address detection
 - Stop bit detection
- Generation and detection of 7-bit/10-bit addressing and general call
- Supports different communication speeds:
 - Standard speed (up to 100 kHz)
 - Fast speed (up to 400 kHz)

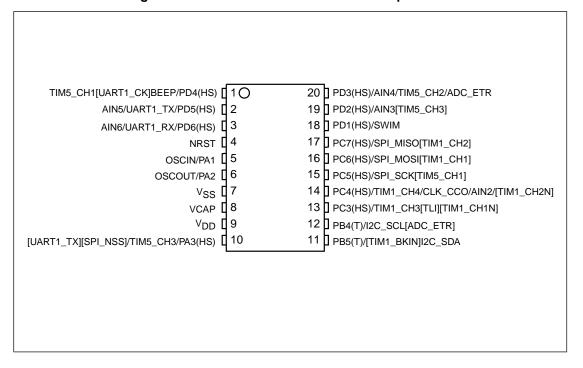
5 Pinout and pin description

Table 4: Legend/abbreviations for pinout tables

Туре	I= Input, O = Output, S = Power supply									
Level	Input	CM = CMOS								
	Output	HS = High sink								
Output speed	O1 = Slow (up to 2 MHz) O2 = Fast (up to 10 MHz) O3 = Fast/slow programmability with slow as default state after res O4 = Fast/slow programmability with fast as default state after res									
Port and control configuration	Input Output	float = floating, wpu = weak pull-up T = True open drain, OD = Open drain, PP = Push pull								
Reset state	Bold X (pin state after internal reset release). Unless otherwise specified, the pin state is the same during phase and after the internal reset release.									

5.1 STM8S903K3/F3 TSSOP20/SO20 pinout

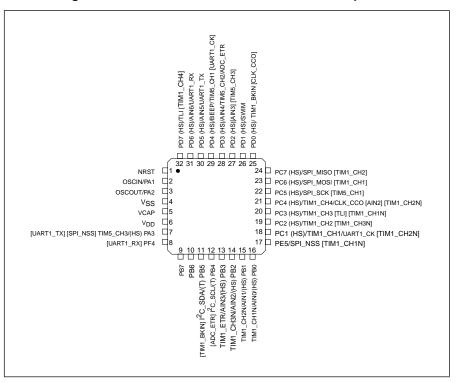
Figure 3: STM8S903K3/F3 TSSOP20/SO20 pinout



- 1. (HS) high sink capability.
- 2. (T) true open drain (P-buffer and protection diode to V_{DD} not implemented).
- **3.** [] alternate function remapping option (if the same alternate function is shown twice, it indicates an exclusive choice not a duplication of the function).

5.2 STM8S903K3/F3 UFQFPN32/LQFP32/SDIP32 pinout

Figure 4: STM8S903K3/F3 UFQFPN32/LQFP32 pinout



- 1. (HS) high sink capability.
- **2.** (T) true open drain (P-buffer and protection diode to V_{DD} not implemented).
- **3.** [] alternate function remapping option (if the same alternate function is shown twice, it indicates an exclusive choice not a duplication of the function).

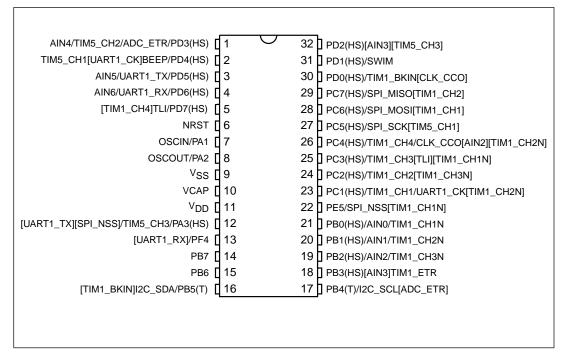


Figure 5: STM8S903K3/F3 SDIP32 pinout

- 1. (HS) high sink capability.
- 2. (T) true open drain (P-buffer and protection diode to V_{DD} not implemented).
- **3.** [] alternate function remapping option (if the same alternate function is shown twice, it indicates an exclusive choice not a duplication of the function).

5.3 Pin description

Table 5: TSSOP20/SO20/UFQFPN32/LQFP32/SDIP32 pin description

1980P	SDIP	UFQFPN	Pin name	Туре	Input							Main Default alternate function		Alternate function after remap [option bit]
SO20	32	LQFP32			floating	wpu	Ext. interrupt	High sink ⁽¹⁾	Speed	OD	PP	(after reset)		[Option bit]
4	6	1	NRST	I/O		<u>x</u>						Reset		
5	7	2	PA1/ OSCIN ⁽²⁾	I/O	<u>x</u>	х	х		01	х	х	Port A1	Resonator/ crystal in	
6	8	3	PA2/ OSCOUT	1/0	<u>x</u>	х	x		O1	х	х	Port A2	Resonator/ crystal out	
7	9	4	V _{SS}	s								Digital	ground	
8	10	5	VCAP	S								1.8 V re	egulator capacitor	
9	11	6	V _{DD}	s								Digital	power supply	
10	12	7	PA3/ TIM5_CH3 [SPI_NSS] [UART1_TX]	I/O	X	х	Х	HS	О3	х	х	Port A3	Timer 52 channel 3	SPI master/ slave select [AFR1]/ UART1 data transmit [AFR1:0]
	13	8	PF4 [UART1_RX]	I/O	<u>x</u>	х			01	х	х	Port F4		UART1 data receive [AFR1:0]
	14	9	РВ7	I/O	<u>x</u>	х	х		01	х	х	Port B7		

1580P	SDIP	UFQFPN/ LQFP32	Pin name	Туре	Input			Output				Main	Default alternate function	Alternate function after remap
	32				floating	wpu	Ext. interrupt	High sink ⁽¹⁾	Speed	OD	PP	function (after reset)		[option bit]
	15	10	PB6	I/O	X	х	x		01	х	х	Port B6		
11	16	11	PB5/ I2C_SDA [TIM1_BKIN]	I/O	X		х		01	T ⁽³⁾		Port B5	I ² C data	Timer 1 - break input [AFR4]
12	17	12	PB4/ I2C_SCL [ADC_ETR]	I/O	X		х		01	T ⁽³⁾		Port B4	I ² C clock	ADC external trigger [AFR4]
	18	13	PB3/ AIN3/TIM1_ETR	I/O	X	х	х	HS	О3	х	х	Port B3	Analog input 3/ Timer 1 external trigger	
	19	14	PB2/ AIN2/ TIM1_CH3N	I/O	X	х	х	HS	О3	х	х	Port B2	Analog input 2/ Timer 1 - inverted channel 3	
	20	15	PB1/ AIN1/ TIM1_CH2N	I/O	X	х	х	HS	О3	х	х	Port B1	Analog input 1/ Timer 1 - inverted channel 2	
	21	16	PB0/ AIN0/ TIM1_CH1N	I/O	X	х	х	HS	О3	х	х	Port B0	Analog input 0/ Timer 1 - inverted channel 1	
	22	17	PE5/ SPI_NSS [TIM1_CH1N]	I/O	X	х	х	HS	О3	х	х	Port E5	SPI master/ slave select	Timer 1 - inverted channel 1 [AFR1:0]
	23	18	PC1/TIM1_CH1/UART1_CK [TIM1_CH2N]	I/O	X	х	х	HS	О3	х	х	Port C1	Timer 1 - channel 1 UART1 clock	Timer 1 - inverted channel 2 [AFR1:0]
	24	19	PC2/ TIM1_CH2 [TIM1_CH3N]	I/O	X	х	х	HS	О3	х	х	Port C2	Timer 1 - channel 2	Timer 1 - inverted channel 3 [AFR1:0]
13	25	20	PC3/TIM1_CH3/TLI/[TIM1_CH1N]	I/O	X	х	х	HS	О3	х	х	Port C3	Timer 1 - channel 3	Top level interrupt [AFR3] Timer 1 inverted channel 1 [AFR7]
14	26	21	PC4/ TIM1_CH4/ CLK_CCO/AIN2/[TIM1_CH2N]	I/O	X	х	х	HS	О3	х	х	Port C4	Timer 1 - channel 4 /configurable clock output	Analog input 2 [AFR2]Timer 1 inverted channel 2 [AFR7]
15	27	22	PC5/SPI_SCK [TIM5_CH1]	I/O	<u>x</u>	х	х	HS	О3	х	х	Port C5	SPI clock	Timer 5 channel 1 [AFR0]
16	28	23	PC6/ SPI_MOSI [TIM1_CH1]	I/O	X	х	х	HS	О3	х	х	Port C6	PI master out/slave in	Timer 1 channel 1 [AFR0]
17	29	24	PC7/ SPI_MISO [TIM1_CH2]	I/O	<u>x</u>	х	х	HS	О3	х	х	Port C7	SPI master in/ slave out	Timer 1 channel 2[AFR0]
	30	25	PD0/ TIM1_BKIN [CLK_CCO]	I/O	<u>x</u>	х	х	HS	О3	х	х	Port D0	Timer 1 - break input	Configurable clock output [AFR5]
18	31	26	PD1/ SWIM ⁽⁴⁾	I/O	х	<u>x</u>	х	HS	O4	х	х	Port D1	SWIM data interface	
19	32	27	PD2/AIN3/ [TIM5_CH3]	I/O	<u>x</u>	х	х	HS	О3	х	х	Port D2		Analog input 3 [AFR2] Timer 52 - channel 3 [AFR1]
20	1	28	PD3/ AIN4/ TIM5_CH2/ ADC_ETR	I/O	X	х	х	HS	О3	х	х	Port D3	Analog input 4 Timer 52 - channel 2/ADC external trigger	
1	2	29	PD4/ TIM5_CH1/ BEEP [UART1_CK]	I/O	x	х	х	HS	О3	х	х	Port D4	Timer 5 - channel 1/BEEP output	UART clock [AFR2]
2	3	30	PD5/ AIN5/ UART1_TX	I/O	x	х	х	HS	О3	х	х	Port D5	Analog input 5/ UART1 data transmit	
3	4	31	PD6/ AIN6/ UART1_RX	I/O	x	х	х	HS	О3	х	х	Port D6	Analog input 6/ UART1 data receive	
	5	32	PD7/ TLI [TIM1_CH4]	I/O	x	х	×	HS	О3	х	х	Port D7	Top level interrupt	Timer 1 - channel 4 [AFR6]

⁽¹⁾ I/O pins used simultaneously for high current source/sink must be uniformly spaced around the package. In addition, the total driven current must respect the absolute maximum ratings (see section "Absolute maximum ratings").

(2) When the MCU is in Halt/Active-halt mode, PA1 is automatically configured in input weak pull up and cannot be used for waking up the device. In this mode, the output state of PA1 is not driven. It is recommended to use PA1 only in input mode if Halt/Active-halt is used in the application.

(3) In the open-drain output column, "T defines a true open-drain I/O (P-buffer and protection diode to V_{DD} are not implemented)

(4) The DRIVE is in its insultability to drive the record phase and after integral reset release.

 $^{^{(4)}}$ The PD1 pin is in input pull-up during the reset phase and after internal reset release.

5.4 Alternate function remapping

As shown in the rightmost column of the pin description table, some alternate functions can be remapped at different I/O ports by programming one of eight AFR (alternate function remap) option bits. When the remapping option is active, the default alternate function is no longer available.

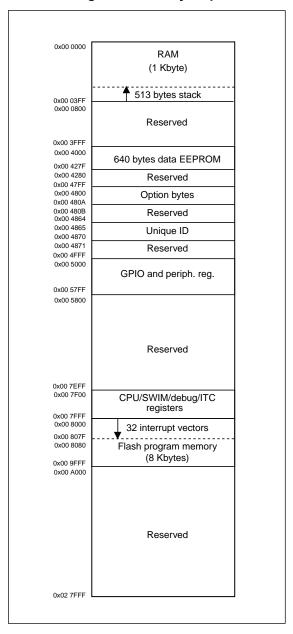
To use an alternate function, the corresponding peripheral must be enabled in the peripheral registers.

Alternate function remapping does not effect GPIO capabilities of the I/O ports (see the GPIO section of the family reference manual, RM0016).

6 Memory and register map

6.1 Memory map

Figure 6: Memory map



6.2 Register map

6.2.1 I/O port hardware register map

Table 6: I/O port hardware register map

Address	Block	Register label	Register name	Reset status
0x00 5000		PA_ODR	Port A data output latch register	0x00
0x00 5001	7	PA_IDR	Port A input pin value register	0xXX
0x00 5002	Port A	PA_DDR	Port A data direction register	0x00
0x00 5003	1	PA_CR1	Port A control register 1	0x00
0x00 5004	7	PA_CR2	Port A control register 2	0x00
0x00 5005		PB_ODR	Port B data output latch register	0x00
0x00 5006	1	PB_IDR	Port B input pin value register	0xXX
0x00 5007	Port B	PB_DDR	Port B data direction register	0x00
0x00 5008	1	PB_CR1	Port B control register 1	0x00
0x00 5009	1	PB_CR2	Port B control register 2	0x00
0x00 500A		PC_ODR	Port C data output latch register	0x00
0x00 500B	1	PB_IDR	Port C input pin value register	0xXX
0x00 500C	Port C	PC_DDR	Port C data direction register	0x00
0x00 500D	1	PC_CR1	Port C control register 1	0x00
0x00 500E	1	PC_CR2	Port C control register 2	0x00
0x00 500F		PD_ODR	Port D data output latch register	0x00
0x00 5010	1	PD_IDR	Port D input pin value register	0xXX
0x00 5011	Port D	PD_DDR	Port D data direction register	0x00
0x00 5012	1	PD_CR1	Port D control register 1	0x02
0x00 5013	1	PD_CR2	Port D control register 2	0x00
0x00 5014		PE_ODR	Port E data output latch register	0x00
0x00 5015	Dow'r	PE_IDR	Port E input pin value register	0xXX
0x00 5016	Port E	PE_DDR	Port E data direction register	0x00
0x00 5017	7	PE_CR1	Port E control register 1	0x00

Address	Block	Register label	Register name	Reset status
0x00 5018	Port E	PE_CR2	Port E control register 2	0x00
0x00 5019		PF_ODR	Port F data output latch register	0x00
0x00 501A		PF_IDR	Port F input pin value register	0xXX
0x00 501B	Port F	PF_DDR	Port F data direction register	0x00
0x00 501C		PF_CR1	Port F control register 1	0x00
0x00 501D]	PF_CR2	Port F control register 2	0x00

6.2.2 General hardware register map

Table 7: General hardware register map

Address	Block	Register label	Register name	Reset status
0x00 501E to 0x00 5059	Reserved	l area (60 bytes)		
0x00 505A	Flash	FLASH_CR1	Flash control register 1	0x00
0x00 505B		FLASH_CR2	Flash control register 2	0x00
0x00 505C		FLASH_NCR2	Flash complementary control register 2	0xFF
0x00 505D		FLASH_FPR	Flash protection register	0x00
0x00 505E		FLASH_NFPR	Flash complementary protection register	0xFF
0x00 505F		FLASH_IAPSR	Flash in-application programming status register	0x00
0x00 5060 to 0x00 5061	Reserved	I area (2 bytes)		
0x00 5062	Flash	FLASH_PUKR	Flash program memory unprotection register	0x00
0x00 5063	Reserved	l area (1 byte)	•	•
0x00 5064	Flash	FLASH _DUKR	Data EEPROM unprotection register	0x00

Address	Block	Register label	Register name	Reset status
0x00 5065 to 0x00 509F	Reserve	d area (59 bytes)		•
0x00 50A0	ITC	EXTI_CR1	External interrupt control register 1	0x00
0x00 50A1		EXTI_CR2	External interrupt control register 2	0x00
0x00 50A2 to 0x00 50B2	Reserve	d area (17 bytes)		,
0x00 50B3	RST	RST_SR	Reset status register	0xXX ⁽¹⁾
0x00 50B4 to 0x00 50BF	Reserve	d area (12 bytes)		
0x00 50C0	CLK	CLK_ICKR	Internal clock control register	0x01
0x00 50C1		CLK_ECKR	External clock control register	0x00
0x00 50C2	Reserve	d area (1 byte)		•
0x00 50C3	CLK	CLK_CMSR	Clock master status register	0xE1
0x00 50C4		CLK_SWR	Clock master switch register	0xE1
0x00 50C5		CLK_SWCR	Clock switch control register	0xXX
0x00 50C6		CLK_CKDIVR	Clock divider register	0x18
0x00 50C7		CLK_PCKENR1	Peripheral clock gating register 1	0xFF
0x00 50C8		CLK_CSSR	Clock security system register	0x00
0x00 50C9		CLK_CCOR	Configurable clock control register	0x00
0x00 50CA		CLK_PCKENR2	Peripheral clock gating register 2	0xFF
0x00 50CB		CLK_CANCCR	CAN clock control register	0x00

Address	Block	Register label	Register name	Reset status
0x00 50CC		CLK_HSITRIMR	HSI clock calibration trimming register	0x00
0x00 50CD		CLK_SWIMCCR	SWIM clock control register	0bXXXX XXX0
0x00 50CE to 0x00 50D0	Reserved	d area (3 bytes)		
0x00 50D1	WWDG	WWDG_CR	WWDG control register	0x7F
0x00 50D2		WWDG_WR	WWDR window register	0x7F
0x00 50D3 to 00 50DF	Reserved	d area (13 bytes)	•	
0x00 50E0	IWDG	IWDG_KR	IWDG key register	0xXX ⁽²⁾
0x00 50E1		IWDG_PR	IWDG prescaler register	0x00
0x00 50E2		IWDG_RLR	IWDG reload register	0xFF
0x00 50E3 to 0x00 50EF	Reserved	d area (13 bytes)	,	
0x00 50F0	AWU	AWU_CSR1	AWU control/status register 1	0x00
0x00 50F1		AWU_APR	AWU asynchronous prescaler buffer register	0x3F
0x00 50F2		AWU_TBR	AWU timebase selection register	0x00
0x00 50F3	BEEP	BEEP_CSR	BEEP control/status register	0x1F
0x00 50F4 to 0x00 50FF	Reserved	d area (12 bytes)	,	
0x00 5200	SPI	SPI_CR1	SPI control register 1	0x00
0x00 5201		SPI_CR2	SPI control register 2	0x00

Address	Block	Register label	Register name	Reset status
0x00 5202		SPI_ICR	SPI interrupt control register	0x00
0x00 5203		SPI_SR	SPI status register	0x02
0x00 5204		SPI_DR	SPI data register	0x00
0x00 5205		SPI_CRCPR	SPI CRC polynomial register	0x07
0x00 5206		SPI_RXCRCR	SPI Rx CRC register	0xFF
0x00 5207		SPI_TXCRCR	SPI Tx CRC register	0xFF
0x00 5208 to 0x00 520F	Reserve	d area (8 bytes)		•
0x00 5210	I ² C	I2C_CR1	I ² C control register 1	0x00
0x00 5211		I2C_CR2	I ² C control register 2	0x00
0x00 5212		I2C_FREQR	I ² C frequency register	0x00
0x00 5213		I2C_OARL	I ² C Own address register low	0x00
0x00 5214		I2C_OARH	I ² C Own address register high	0x00
0x00 5215		Reserved		
0x00 5216		I2C_DR	I ² C data register	0x00
0x00 5217		I2C_SR1	I ² C status register 1	0x00
0x00 5218		I2C_SR2	I ² C status register 2	0x00
0x00 5219		I2C_SR3	I ² C status register 3	0x0x
0x00 521A		I2C_ITR	I ² C interrupt control register	0x00
0x00 521B		I2C_CCRL	I ² C Clock control register low	0x00

Address	Block	Register label	Register name	Reset status
0x00 521C		I2C_CCRH	I ² C Clock control register high	0x00
0x00 521D		I2C_TRISER	I ² C TRISE register	0x02
0x00 521E		I2C_PECR	I ² C packet error checking register	0x00
0x00 521F to 0x00 522F	Reserve	d area (17 bytes)		1
0x00 5230	UART1	UART1_SR	UART1 status register	0xC0
0x00 5231		UART1_DR	UART1 data register	0xXX
0x00 5232		UART1_BRR1	UART1 baud rate register 1	0x00
0x00 5233		UART1_BRR2	UART1 baud rate register 2	0x00
0x00 5234		UART1_CR1	UART1 control register 1	0x00
0x00 5235		UART1_CR2	UART1 control register 2	0x00
0x00 5236		UART1_CR3	UART1 control register 3	0x00
0x00 5237		UART1_CR4	UART1 control register 4	0x00
0x00 5238		UART1_CR5	UART1 control register 5	0x00
0x00 5239		UART1_GTR	UART1 guard time register	0x00
0x00 523A		UART1_PSCR	UART1 precaler register	0x00
0x00 523B to 0x00 523F	Reserve	d area (21 bytes)		l
0x00 5250	TIM1	TIM1_CR1	TIM1 control register 1	0x00
0x00 5251		TIM1_CR2	TIM1 control register 2	0x00
			<u> </u>	

Address	Block	Register label	Register name	Reset status
0x00 5252		TIM1_SMCR	TIM1 slave mode control register	0x00
0x00 5253]	TIM1_ETR	TIM1 external trigger register	0x00
0x00 5254]	TIM1_IER	TIM1 interrupt enable register	0x00
0x00 5255]	TIM1_SR1	TIM1 status register 1	0x00
0x00 5256	-	TIM1_SR2	TIM1 status register 2	0x00
0x00 5257	-	TIM1_EGR	TIM1 event generation register	0x00
0x00 5258	-	TIM1_CCMR1	TIM1 capture/compare mode register 1	0x00
0x00 5259]	TIM1_CCMR2	TIM1 capture/compare mode register 2	0x00
0x00 525A]	TIM1_CCMR3	TIM1 capture/compare mode register 3	0x00
0x00 525B]	TIM1_CCMR4	TIM1 capture/compare mode register 4	0x00
0x00 525C		TIM1_CCER1	TIM1 capture/compare enable register 1	0x00
0x00 525D]	TIM1_CCER2	TIM1 capture/compare enable register 2	0x00
0x00 525E]	TIM1_CNTRH	TIM1 counter high	0x00
0x00 525F		TIM1_CNTRL	TIM1 counter low	0x00
0x00 5260		TIM1_PSCRH	TIM1 prescaler register high	0x00
0x00 5261		TIM1_PSCRL	TIM1 prescaler register low	0x00
0x00 5262		TIM1_ARRH	TIM1 auto-reload register high	0xFF
0x00 5263		TIM1_ARRL	TIM1 auto-reload register low	0xFF
0x00 5264		TIM1_RCR	TIM1 repetition counter register	0x00
0x00 5265		TIM1_CCR1H	TIM1 capture/compare register 1 high	0x00

Address	Block	Register label	Register name	Reset status
0x00 5266		TIM1_CCR1L	TIM1 capture/compare register 1 low	0x00
0x00 5267		TIM1_CCR2H	TIM1 capture/compare register 2 high	0x00
0x00 5268		TIM1_CCR2L	TIM1 capture/compare register 2 low	0x00
0x00 5269		TIM1_CCR3H	TIM1 capture/compare register 3 high	0x00
0x00 526A		TIM1_CCR3L	TIM1 capture/compare register 3 low	0x00
0x00 526B		TIM1_CCR4H	TIM1 capture/compare register 4 high	0x00
0x00 526C		TIM1_CCR4L	TIM1 capture/compare register 4 low	0x00
0x00 526D		TIM1_BKR	TIM1 break register	0x00
0x00 526E		TIM1_DTR	TIM1 dead-time register	0x00
0x00 526F		TIM1_OISR	TIM1 output idle state register	0x00
0x00 5270 to 0x00 52FF	Reserve	d area (147 bytes)		,
0x00 5300	TIM5	TIM5_CR1	TIM5 control register 1	0x00
0x00 5301		TIM5_CR2	TIM5 control register 2	0x00
0x00 5302		TIM5_SMCR	TIM5 slave mode control register	0x00
0x00 5303		TIM5_IER	TIM5 interrupt enable register	0x00
0x00 5304		TIM5_SR1	TIM5 status register 1	0x00
0x00 5305		TIM5_SR2	TIM5 status register 2	0x00
0x00 5306		TIM5_EGR	TIM5 event generation register	0x00
0x00 5307		TIM5_CCMR1	TIM5 capture/compare mode register 1	0x00

Address	Block	Register label	Register name	Reset status
0x00 5308		TIM5_CCMR2	TIM5 capture/compare mode register 2	0x00
0x00 5309		TIM5_CCMR3	TIM5 capture/compare mode register 3	0x00
0x00 530A		TIM5_CCER1	TIM5 capture/compare enable register 1	0x00
0x00 530B		TIM5_CCER2	TIM5 capture/compare enable register 2	0x00
00 530C0x		TIM5_CNTRH	TIM5 counter high	0x00
0x00 530D		TIM5_CNTRL	TIM5 counter low	0x00
0x00 530E		TIM5_PSCR	TIM5 prescaler register	0x00
0x00 530F		TIM5_ARRH	TIM5 auto-reload register high	0xFF
0x00 5310		TIM5_ARRL	TIM5 auto-reload register low	0xFF
0x00 5311		TIM5_CCR1H	TIM5 capture/compare register 1 high	0x00
0x00 5312		TIM5_CCR1L	TIM5 capture/compare register 1 low	0x00
0x00 5313		TIM5_CCR2H	TIM5 capture/compare register 2 high	0x00
0x00 5314		TIM5_CCR2L	TIM5 capture/compare register 2 low	0x00
0x00 5315		TIM5_CCR3H	TIM5 capture/compare register 3 high	0x00
0x00 5316		TIM5_CCR3L	TIM5 capture/compare register 3 low	0x00
0x00 5317 to 0x00 533F	Reserve	d area (43 bytes)		,
0x00 5340	TIM6	TIM6_CR1	TIM6 control register 1	0x00
0x00 5341		TIM6_CR2	TIM6 control register 2	0x00
0x00 5342		TIM6_SMCR	TIM6 slave mode control register	0x00

Address	Block	Register label	Register name	Reset status
0x00 5343		TIM6_IER	TIM6 interrupt enable register	0x00
0x00 5344		TIM6_SR	TIM6 status register	0x00
0x00 5345		TIM6_EGR	TIM6 event generation register	0x00
0x00 5346		TIM6_CNTR	TIM6 counter	0x00
0x00 5347		TIM6_PSCR	TIM6 prescaler register	0x00
0x00 5348		TIM6_ARR	TIM6 auto-reload register	0xFF
0x00 5349 to 0x00 53DF	Reserve	d area (153 bytes)		•
0x00 53E0 to 0x00 53F3	ADC1	ADC _DBxR	ADC data buffer registers	0x00
0x00 53F4 to 0x00 53FF	Reserve	d area (12 bytes)		
0x00 5400	ADC1 cont'd	ADC _CSR	ADC control/status register	0x00
0x00 5401		ADC_CR1	ADC configuration register 1	0x00
0x00 5402		ADC_CR2	ADC configuration register 2	0x00
0x00 5403		ADC_CR3	ADC configuration register 3	0x00
0x00 5404		ADC_DRH	ADC data register high	0xXX
0x00 5405		ADC_DRL	ADC data register low	0xXX
0x00 5406		ADC_TDRH	ADC Schmitt trigger disable register high	0x00
0x00 5407		ADC_TDRL	ADC Schmitt trigger disable register low	0x00
0x00 5408		ADC_HTRH	ADC high threshold register high	0x03

Address	Block	Register label	Register name	Reset status
0x00 5409		ADC_HTRL	ADC high threshold register low	0xFF
0x00 540A		ADC_LTRH	ADC low threshold register high	0x00
0x00 540B		ADC_LTRL	ADC low threshold register low	0x00
0x00 540C		ADC_AWSRH	ADC analog watchdog status register high	0x00
0x00 540D		ADC_AWSRL	ADC analog watchdog status register low	0x00
0x00 540E		ADC _AWCRH	ADC analog watchdog control register high	0x00
0x00 540F		ADC_AWCRL	ADC analog watchdog control register low	0x00
0x00 5410 to 0x00 57FF	Reserved	area (1008 bytes)		•

⁽¹⁾Depends on the previous reset source.

6.2.3 CPU/SWIM/debug module/interrupt controller registers

Table 8: CPU/SWIM/debug module/interrupt controller registers

Address	Block	Register label	Register name	Reset status
0x00 7F00	CPU ⁽¹⁾	А	Accumulator	0x00
0x00 7F01		PCE	Program counter extended	0x00
0x00 7F02		PCH	Program counter high	0x00
0x00 7F03		PCL	Program counter low	0x00
0x00 7F04		XH	X index register high	0x00
0x00 7F05		XL	X index register low	0x00
0x00 7F06		YH	Y index register high	0x00
0x00 7F07		YL	Y index register low	0x00
0x00 7F08		SPH	Stack pointer high	0x03

⁽²⁾ Write only register.

Address	Block	Register label	Register name	Reset status
0x00 7F09		SPL	Stack pointer low	0xFF
0x00 7F0A		CCR	Condition code register	0x28
0x00 7F0B to 0x00 7F5F		Res	served area (85 bytes)	
0x00 7F60	CPU	CFG_GCR	Global configuration register	0x00
0x00 7F70		ITC_SPR1	Interrupt software priority register 1	0xFF
0x00 7F71		ITC_SPR2	Interrupt software priority register 2	0xFF
0x00 7F72		ITC_SPR3	Interrupt software priority register 3	0xFF
0x00 7F73	ITC	ITC_SPR4	Interrupt software priority register 4	0xFF
0x00 7F74		ITC_SPR5	Interrupt software priority register 5	0xFF
0x00 7F75		ITC_SPR6	Interrupt software priority register 6	0xFF
0x00 7F76		ITC_SPR7	Interrupt software priority register 7	0xFF
0x00 7F77		ITC_SPR8	Interrupt software priority register 8	0xFF
0x00 7F78 to 0x00 7F79	Reserved area (2 bytes)			
0x00 7F80	SWIM	SWIM_CSR SWIM control status register		0x00
0x00 7F81 to 0x00 7F8F	Reserved area (15 bytes)			
0x00 7F90		DM_BK1RE	DM breakpoint 1 register extended byte	0xFF
0x00 7F91		DM_BK1RH	DM breakpoint 1 register high byte	0xFF
0x00 7F92	7F92 DM_BK1RL DM breakpoint 1 register low byte		DM breakpoint 1 register low byte	0xFF
0x00 7F93	0 7F93 DM_BK2RE DM breakpoint 2 register extend byte		DM breakpoint 2 register extended byte	0xFF
0x00 7F94			0xFF	
0x00 7F95	- DM -			0xFF
0x00 7F96		7F96 DM_CR1 DM debug module control register		0x00
0x00 7F97		7F97 DM_CR2 DM debug module control register 2		DM debug module control register 2
0x00 7F98		DM_CSR1	DM debug module control/status register 1	0x10
0x00 7F99		DM_CSR2	DM debug module control/status register 2	0x00

Address	Block	Register label	Register name	Reset status
0x00 7F9A		DM_ENFCTR	DM enable function register	0xFF
0x00 7F9B to 0x00 7F9F	Reserved area (5 bytes)			

⁽¹⁾ Accessible by debug module only

7 Interrupt vector mapping

Table 9: Interrupt mapping

IRQ no.	Source block	Description	Wakeup from halt mode	Wakeup from active-halt mode	Vector address
	RESET	Reset	Yes	Yes	0x00 8000
	TRAP	Software interrupt	-	-	0x00 8004
0	TLI	External top level interrupt	-	-	0x00 8008
1	AWU	Auto wake up from halt	-	Yes	0x00 800C
2	CLK	Clock controller	-	-	0x00 8010
3	EXTI0	Port A external interrupts	Yes ⁽¹⁾	Yes ⁽¹⁾	0x00 8014
4	EXTI1	Port B external interrupts	Yes	Yes	0x00 8018
5	EXTI2	Port C external interrupts	Yes	Yes	0x00 801C
6	EXTI3	Port D external interrupts	Yes	Yes	0x00 8020
7	EXTI4	Port E external interrupts	Yes	Yes	0x00 8024
8	EXTI5	Port F			0x00 8028
9		Reserved	-	-	0x00 802C
10	SPI	End of transfer	Yes	Yes	0x00 8030
11	TIM1	TIM1 update/ overflow/ underflow/ trigger/ break	-	-	0x00 8034
12	TIM1	TIM1 capture/ compare	-	-	0x00 8038
13	TIM5	TIM5 update/ overflow/ trigger	-	-	0x00 803C
14	TIM5	TIM5 capture/ compare	-	-	0x00 8040
15		Reserved	-	-	0x00 8044
16		Reserved	-	-	0x00 8048
17			-	-	0x00 804C
18			-	-	0x00 8050
19	I ² C	I ² C interrupt	Yes	Yes	0x00 8054
20		Reserved	-	-	0x00 8058
21		Reserved	-	-	0x00 805C
22	ADC1	ADC1 end of conversion/ analog watchdog interrupt	-	-	0x00 8060

	Source block	Description	•	Wakeup from active-halt mode	Vector address
23	TIM6	TIM6 update/ overflow/ trigger	-	-	0x00 8064
24	Flash	EOP/ WR_PG_DIS	-	-	0x00 8068
Reserved				0x00 806C to 0x00 807C	

⁽¹⁾ Except PA1

8 Option bytes

Option bytes contain configurations for device hardware features as well as the memory protection of the device. They are stored in a dedicated block of the memory. Except for the ROP (read-out protection) byte, each option byte has to be stored twice, in a regular form (OPTx) and a complemented one (NOPTx) for redundancy.

Option bytes can be modified in ICP mode (via SWIM) by accessing the EEPROM address shown in the table below.

Option bytes can also be modified 'on the fly' by the application in IAP mode, except the ROP option that can only be modified in ICP mode (via SWIM).

Refer to the STM8S Flash programming manual (PM0051) and STM8 SWIM communication protocol and debug module user manual (UM0470) for information on SWIM programming procedures.

Addr. Option Option Option bits Factory default name byte no. setting 2 0 6 5 3 0x4800 Read-out OPT0 00h **ROP** [7:0] protection (ROP) 0x4801 00h User boot OPT1 **UBC** [7:0] code(UBC) 0x4802 NOPT1 FFh NUBC [7:0] OPT2 AFR5 AFR4 AFR3 AFR2 AFR1 AFR0 00h 0x4803 Alternate AFR7 AFR6 function 0x4804 NOPT2 NAFR7 NAFR6 NAFR5 NAFR4 NAFR3 NAFR2 NAFR1 NAFR0 FFh remapping (AFR) OPT3 HSI LSI_EN **IWDG** WWDG WWDG 00h 0x4805h Miscell. Reserved **TRIM** HW option HW HALT FFh NOPT3 NHSI NLSI_ NIWDG **NWWDG** NWW 0x4806 Reserved TRIM ΕN HW HW G HALT **EXT CLK** PRS C0 0x4807 Clock OPT4 Reserved CKAWU PRS C1 00h option SEL NOPT4 NCKA NPRSC1 NPR FFh 0x4808 Reserved **NEXT** CLK WUSEL SC0 HSECNT [7:0] 0x4809 HSE clock OPT5 00hstartup NOPT5 NHSECNT [7:0] FFh 0x480A

Table 10: Option bytes

Table 11: Option byte description

Option byte no.	Description
OPT0	ROP[7:0] Memory readout protection (ROP)
	0xAA: Enable readout protection (write access via SWIM protocol)

Option byte no.	Description		
	Note: Refer to the family reference manual (RM0016) section on Flash/EEPROM memory readout protection for details.		
OPT1	UBC[7:0] User boot code area		
	0x00: no UBC, no write-protection		
	0x01: Page 0 defined as UBC, memory write-protected		
	0x02: Pages 0 to 1 defined as UBC, memory write-protected.		
	Page 0 and 1 contain the interrupt vectors.		
	0x7F: Pages 0 to 126 defined as UBC, memory write-protected		
	Other values: Pages 0 to 127 defined as UBC, memory write-protected		
	Note: Refer to the family reference manual (RM0016) section on Flash write protection for more details.		
OPT2	AFR[7:0]		
	Refer to following section for alternate function remapping decriptions of bits [7:2] and [1:0] respectively.		
OPT3	HSITRIM:High speed internal clock trimming register size		
	0: 3-bit trimming supported in CLK_HSITRIMR register		
	1: 4-bit trimming supported in CLK_HSITRIMR register		
	LSI_EN:Low speed internal clock enable		
	0: LSI clock is not available as CPU clock source		
	1: LSI clock is available as CPU clock source		
	IWDG_HW: Independent watchdog		
	0: IWDG Independent watchdog activated by software		
	1: IWDG Independent watchdog activated by hardware		
	WWDG_HW: Window watchdog activation		
	0: WWDG window watchdog activated by software		
	1: WWDG window watchdog activated by hardware		
	WWDG_HALT: Window watchdog reset on halt		

Option byte no.	Description	
	0: No reset generated on halt if WWDG active	
	1: Reset generated on halt if WWDG active	
OPT4	EXTCLK: External clock selection	
	0: External crystal connected to OSCIN/OSCOUT	
	1: External clock signal on OSCIN	
	CKAWUSEL:Auto wake-up unit/clock	
	0: LSI clock source selected for AWU	
	1: HSE clock with prescaler selected as clock source for for AW	
	PRSC[1:0] AWU clock prescaler	
	0x: 16 MHz to 128 kHz prescaler	
	10: 8 MHz to 128 kHz prescaler	
	11: 4 MHz to 128 kHz prescaler	
OPT5	HSECNT[7:0]:HSE crystal oscillator stabilization time	
	0x00: 2048 HSE cycles	
	0xB4: 128 HSE cycles	
	0xD2: 8 HSE cycles	
	0xE1: 0.5 HSE cycles	

8.1 STM8S903K3/F3 alternate function remapping bits

Table 12: STM8S903K3 alternate function remapping bits [7:2] for 32-pin packages

Description ⁽¹⁾
AFR7 Alternate function remapping option 7
0: AFR7 remapping option inactive: Default alternate functions ⁽²⁾ .
1: Port C3 alternate function = TIM1_CH1N; port C4 alternate function = TIM1_CH2N.
AFR6 Alternate function remapping option 6
0: AFR6 remapping option inactive: Default alternate function ⁽²⁾ .
1: Port D7 alternate function = TIM1_CH4.

Option byte no.	Description ⁽¹⁾	
	AFR5 Alternate function remapping option 5	
	0: AFR5 remapping option inactive: Default alternate function ⁽²⁾ .	
	1: Port D0 alternate function = CLK_CCO.	
	AFR4 Alternate function remapping option 4	
	0: AFR4 remapping option inactive: Default alternate functions ⁽²⁾ .	
	1: Port B4 alternate function = ADC_ETR; port P5 alternate function = TIM1_BKIN.	
	AFR3 Alternate function remapping option 3	
	0: AFR3 remapping option inactive: Default alternate function ⁽²⁾ .	
	1: Port C3 alternate function = TLI.	
	AFR2 Alternate function remapping option 2	
	0: AFR2 remapping option inactive: Default alternate functions ⁽²⁾ .	
	1: Port C4 alternate function = AIN2; port D2 alternate function = AIN3; port D4 alternate function = UART1_CK.	

 $^{^{\}left(1\right) }$ Do not use more than one remapping option in the same port.

Table 13: STM8S903F3 alternate function remapping bits [7:2] for 20-pin packages

Option byte no.	Description ⁽¹⁾
OPT2	AFR7 Alternate function remapping option 7
	0: AFR7 remapping option inactive: Default alternate functions ⁽²⁾
	1: Port C3 alternate function = TIM1_CH1N; port C4 alternate function = TIM1_CH2N.
	AFR6 Alternate function remapping option 6
	Reserved.
	AFR5 Alternate function remapping option 5
	Reserved.
	AFR4 Alternate function remapping option 4
	0: AFR4 remapping option inactive: Default alternate functions ⁽²⁾ .
	1: Port B4 alternate function = ADC_ETR; port P5 alternate function = TIM1_BKIN.
	AFR3 Alternate function remapping option 3

⁽²⁾ Refer to pinout description.

Option byte no.	Description ⁽¹⁾
	0: AFR3 remapping option inactive: Default alternate function ⁽²⁾ .
	1: Port C3 alternate function = TLI.
	AFR2 Alternate function remapping option 2
	Reserved.

 $^{^{(1)}}$ Do not use more than one remapping option in the same port.

Table 14: STM8S903K3 alternate function remapping bits [1:0] for 32-pin packages

AFR1 option bit value	AFR0 option bit value	I/O port	Alternate function mapping
0	0	AFR1 and AFR0 remapping options inactive: Default alternate functions ⁽¹⁾	
0	1	PC5	TIM5_CH1
		PC6	TIM1_CH1
		PC7	TIM1_CH2
1	0	PA3	SPI_NSS
		PD2	TIM5_CH3
		PD2	TIM5_CH3
		PC5	TIM5_CH1
		PC6	TIM1_CH1
		PC7	TIM1_CH2
1	1	PC2	TIM1_CH3N
		PC1	TIM1_CH2N
		PE5	TIM1_CH1N
		PA3	UART1_TX
		PF4	UART1_RX

⁽¹⁾ Refer to pinout description.

⁽²⁾ Refer to pinout description.

Table 15: STM8S903F3 alternate function remapping bits [1:0] for 20-pin packages

AFR1 option bit value	AFR0 option bit value	I/O port	Alternate function mapping
0	0	AFR1 and AF Default alterr	R0 remapping options inactive:
0	1	PC5	TIM5_CH1
		PC6	TIM1_CH1
		PC7	TIM1_CH2
1	0	PA3	SPI_NSS
		PD2	TIM5_CH3
		PD2	TIM5_CH3
		PC5	TIM5_CH1
		PC6	TIM1_CH1
		PC7	TIM1_CH2
1	1	PC2	_
		PC1	_
		PE5	TIM1_CH1N
		PA3	UART1_TX
		PF4	UART1_RX

⁽¹⁾ Refer to pinout description.

9 Unique ID

The devices feature a 96-bit unique device identifier which provides a reference number that is unique for any device and in any context. The 96 bits of the identifier can never be altered by the user.

The unique device identifier can be read in single bytes and may then be concatenated using a custom algorithm.

The unique device identifier is ideally suited:

- For use as serial numbers
- For use as security keys to increase the code security in the program memory while using and combining this unique ID with software cryptograhic primitives and protocols before programming the internal memory.
- To activate secure boot processes

Table 16: Unique ID registers (96 bits)

Address	Content	Unique	e ID bits	S					
	description	7	6	5	4	3	2	1	0
0x4865	X co-ordinate				U_	ID[7:0]			
0x4866	on the wafer				U_I	D[15:8]			
0x4867	Y co-ordinate				U_II	D[23:16]		
0x4868	on the wafer				U_II	D[31:24]		
0x4869	Wafer number				U_II	D[39:32 _]]		
0x486A					U_II	D[47:40 _]]		
0x486B					U_II	D[55:48 _]]		
0x486C					U_II	D[63:56 _]]		
0x486D	Lot number				U_II	D[71:64]		
0x486E					U_II	D[79:72 _]]		
0x486F					U_II	D[87:80 _]]		
0x4870					U_II	D[95:88 _]]		

10 Electrical characteristics

10.1 Parameter conditions

Unless otherwise specified, all voltages are referred to $V_{\rm SS}$.

10.1.1 Minimum and maximum values

Unless otherwise specified the minimum and maximum values are guaranteed in the worst conditions of ambient temperature, supply voltage and frequencies by tests in production on 100 % of the devices with an ambient temperature at $T_A = 25$ °C and $T_A = T_{Amax}$ (given by the selected temperature range).

Data based on characterization results, design simulation and/or technology characteristics are indicated in the table footnotes and are not tested in production. Based on characterization, the minimum and maximum values refer to sample tests and represent the mean value plus or minus three times the standard deviation (mean \pm 3 Σ).

10.1.2 Typical values

Unless otherwise specified, typical data are based on T_A = 25 °C, V_{DD} = 5 V. They are given only as design guidelines and are not tested.

Typical ADC accuracy values are determined by characterization of a batch of samples from a standard diffusion lot over the full temperature range, where 95% of the devices have an error less than or equal to the value indicated (mean \pm 2 Σ).

10.1.3 Typical curves

Unless otherwise specified, all typical curves are given only as design guidelines and are not tested.

10.1.4 Loading capacitor

The loading conditions used for pin parameter measurement are shown in the following figure.

50 pF

Figure 7: Pin loading conditions

10.1.5 Pin input voltage

The input voltage measurement on a pin of the device is described in the following figure.

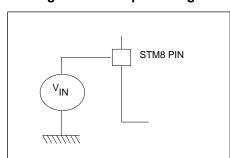


Figure 8: Pin input voltage

10.2 Absolute maximum ratings

Stresses above those listed as 'absolute maximum ratings' may cause permanent damage to the device. This is a stress rating only and functional operation of the device under these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

Symbol	Ratings	Min	Max	Unit
V _{DDx} - V _{SS}	Supply voltage ⁽¹⁾	-0.3	6.5	
V _{IN}	Input voltage on true open drain pins ⁽²⁾	V _{SS} - 0.3	6.5	V
	Input voltage on any other pin ⁽²⁾	V _{SS} - 0.3	V _{DD} + 0.3	
V _{DDx} - V _{DD}	Variations between different power pins		50	
V _{SSx} - V _{SS}	Variations between all the different ground pins		50	mV
V _{ESD}	Electrostatic discharge voltage	See "Absol maximum r (electrical s	atings	

Table 17: Voltage characteristics

 $^{^{(1)}}$ All power (V_{DD}) and ground (V_{SS}) pins must always be connected to the external power supply

 $^{^{(2)}}$ $I_{\text{INJ(PIN)}}$ must never be exceeded. This is implicitly insured if V_{IN} maximum is respected. If V_{IN} maximum cannot be respected, the injection current must be limited externally to the $I_{\text{INJ(PIN)}}$ value. A positive injection is induced by $V_{\text{IN}} > V_{\text{DD}}$ while a negative injection is induced by $V_{\text{IN}} < V_{\text{SS}}$. For true open-drain pads, there is no positive injection current, and the corresponding V_{IN} maximum must always be respected

Table 18: Current characteristics

Symbol	Ratings	Max ⁽¹⁾	Unit
I _{VDD}	Total current into V _{DD} power lines (source) ⁽²⁾	100	
I _{VSS}	Total current out of V _{SS} ground lines (sink) ⁽²⁾	80	
I _{IO}	Output current sunk by any I/O and control pin	20	
	Output current source by any I/Os and control pin	- 20	mA
I _{INJ(PIN)} (3) (4)	Injected current on NRST pin	± 4	IIIA
	Injected current on OSCIN pin	± 4	
	Injected current on any other pin ⁽⁵⁾	± 4	
ΣΙ _{INJ(PIN)} ⁽³⁾	Total injected current (sum of all I/O and control pins) ⁽⁵⁾	± 20	

⁽¹⁾ Data based on characterization results, not tested in production.

Table 19: Thermal characteristics

Symbol	Ratings	Value	Unit
T _{STG}	Storage temperature range	-65 to +150	°C
T _J	Maximum junction temperature	150	

 $^{^{(2)}}$ All power (V_{DD}) and ground (V_{SS}) pins must always be connected to the external supply.

 $^{^{(3)}}$ $I_{\text{INJ(PIN)}}$ must never be exceeded. This is implicitly insured if V_{IN} maximum is respected. If V_{IN} maximum cannot be respected, the injection current must be limited externally to the $I_{\text{INJ(PIN)}}$ value. A positive injection is induced by $V_{\text{IN}} > V_{\text{DD}}$ while a negative injection is induced by $V_{\text{IN}} < V_{\text{SS}}$. For true open-drain pads, there is no positive injection current, and the corresponding V_{IN} maximum must always be respected

⁽⁴⁾ ADC accuracy vs. negative injection current: Injecting negative current on any of the analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to standard analog pins which may potentially inject negative current. Any positive injection current within the limits specified for $I_{\text{INJ(PIN)}}$ and $\Sigma I_{\text{INJ(PIN)}}$ in the I/O port pin characteristics section does not affect the ADC accuracy.

When several inputs are submitted to a current injection, the maximum $\Sigma I_{INJ(PIN)}$ is the absolute sum of the positive and negative injected currents (instantaneous values). These results are based on characterization with $\Sigma I_{INJ(PIN)}$ maximum current injection on four I/O port pins of the device.

10.3 Operating conditions

Table 20: General operating conditions

Symbol	Parameter	Conditions	Min	Max	Unit
f _{CPU}	Internal CPU clock frequency		0	16	MHz
V_{DD}	Standard operating voltage		2.95	5.5	V
VCAP	C _{EXT} : capacitance of external capacitor ⁽¹⁾		470	3300	nF
	ESR of external capacitor ⁽¹⁾	at 1 MHz	-	0.3	Ω
	ESL of external capacitor ⁽¹⁾		-	15	nH
P _D ⁽²⁾	Power dissipation at T _A = 85 °C	TSSOP20	-	182	mW
	for suffix 6	SO20W	-	1000	
		LQFP32	-	333	
		UFQFPN32	-	526	
		SDIP32	-	333	
	Power dissipation at T _A = 125	TSSOP20	-	45	
	°C for suffix 3	SO20W	-	250	
		LQFP32	-	83	
		UFQFPN32	-	132	
		SDIP32	-	83	
T _A	Ambient temperature for 6 suffix version	Maximum power dissipation	-40	85	°C
	Ambient temperature for 3 suffix version	Maximum power dissipation	-40	125	
T _J	Junction temperature range	6 suffix version	-40	105	
		3 suffix version	-40	130 ⁽³⁾	

⁽¹⁾ This parameter range must be respected for the full application range, and taking into account the physical capacitor characteristics and tolerance.

 $^{^{(2)}}$ To calculate $P_{Dmax}(T_A)$, use the formula P_{Dmax} = $(T_{Jmax}$ - $T_A)/\Theta_{JA}$ (see *Thermal characteristics*) with the value for T_{Jmax} given in the current table and the value for Θ_{JA} given in *Thermal characteristics*.

 $^{^{(3)}}T_{Jmax}$ is given by the test limit. Above this value the product behavior is not guaranteed.

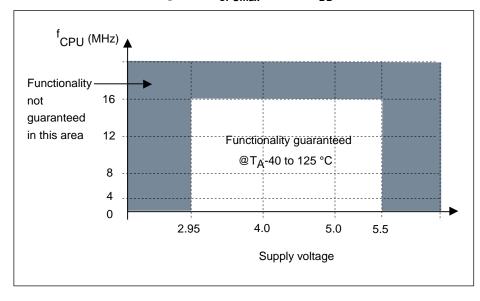


Figure 9: f_{CPUmax} versus V_{DD}

Table 21: Operating conditions at power-up/power-down

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
t _{VDD}	V _{DD} rise time rate		2		∞	μs/V
	V _{DD} fall time rate ⁽¹⁾		2		∞	
t _{TEMP}	Reset releasedelay	V _{DD} rising			1.7	ms
V _{IT+}	Power-on reset threshold		2.6	2.7	2.85	>
V _{IT-}	Brown-out reset threshold		2.5	2.65	2.8	
V _{HYS(BOR)}	Brown-out reset hysteresis			70		mV

 $^{^{(1)}}$ Reset is always generated after a t_{TEMP} delay. The application must ensure that V_{DD} is still above the minimum opperating voltage (V_{DD} min) when the t_{TEMP} delay has elapsed.

10.3.1 VCAP external capacitor

Stabilization for the main regulator is achieved connecting an external capacitor C_{EXT} to the V_{CAP} pin. C_{EXT} is specified in the Operating conditions section. Care should be taken to limit the series inductance to less than 15 nH.

C ESL
ESR
R_{Leak}

Figure 10: External capacitor C_{EXT}

1. ESR is the equivalent series resistance and ESL is the equivalent inductance.

10.3.2 Supply current characteristics

The current consumption is measured as described in *Pin input voltage*.

10.3.2.1 Total current consumption in run mode

The MCU is placed under the following conditions:

- $\bullet~$ All I/O pins in input mode with a static value at $\rm V_{DD}$ or $\rm V_{SS}$ (no load)
- All peripherals are disabled (clock stopped by peripheral clock gating registers) except if explicitly mentioned.

Subject to general operating conditions for V_{DD} and T_{A} .

Table 22: Total current consumption with code execution in run mode at V_{DD} = 5 V

Symbol	Parameter	Conditions		Тур	Max ⁽¹⁾	Unit
			HSE crystal osc. (16 MHz)	2.3		
		f _{CPU} = f _{MASTER} = 16 MHz	HSE user ext. clock (16 MHz)	2	2.35	
			HSI RC osc. (16 MHz)	1.7	2	
	Supply current	$f_{CPU} = f_{MASTER}/128 =$	HSE user ext. clock (16 MHz)	0.86		
	in run mode, code executed from RAM $ f_{CPU} = f_{MASTER}/128 = 15.625 \text{ kHz} $ $ f_{CPU} = f_{MASTER} = 128 \text{ kHz} $	HSI RC osc. (16 MHz)	0.7	0.87		
I _{DD(RUN)}		CPU - MASTER, 120 -	HSI RC osc. (16 MHz/8)	0.46	0.58	mA
			LSI RC osc. (128 kHz)	0.41	0.55	
	Supply current	current	HSE crystal osc. (16 MHz)	4.5		
	in run mode, code executed	f _{CPU} = f _{MASTER} = 16 MHz	HSE user ext. clock (16 MHz)	4.3	4.75	
	from Flash		HSI RC osc. (16 MHz)	3.7	4.5	

Symbol	Parameter	Conditions		Тур	Max ⁽¹⁾	Unit
l. in run mod		f _{CPU} = f _{MASTER} = 2 MHz	HSI RC osc. (16 MHz/8) ⁽²⁾	0.84	1.05	
	Supply current in run mode,	f _{CPU} = f _{MASTER} /128 = 125 kHz	HSI RC osc. (16 MHz)	0.72	0.9	mA
I _{DD(RUN)}	code executed from Flash	f _{CPU} = f _{MASTER} /128 = 15.625 kHz	HSI RC osc. (16 MHz/8)	0.46	0.58	IIIA
		f _{CPU} = f _{MASTER} = 128 kHz	LSI RC osc. (128 kHz)	0.42	0.57	

⁽¹⁾ Data based on characterization results, not tested in production.

Table 23: Total current consumption with code execution in run mode at $V_{\rm DD}$ = 3.3 V

Symbol	Parameter	Conditions		Тур	Max ⁽¹⁾	Unit	
		f -f -	HSE crystal osc. (16 MHz)	1.8			
		f _{CPU} = f _{MASTER} = 16 MHz	HSE user ext. clock (16 MHz)	2	2.3		
			HSI RC osc. (16 MHz)	1.5	2		
	Supply current	f _{CPU} = f _{MASTER} /	HSE user ext. clock (16 MHz)	0.81			
	in run mode, code executed	128 = 125 kHz	HSI RC osc. (16 MHz)	0.7	0.87		
	from RAM	from RAM	f _{CPU} = f _{MASTER} / 128 = 15.625 kHz	HSI RC osc. (16 MHz/8)	0.46	0.58	
I _{DD(RUN)}		f _{CPU} = f _{MASTER} = 128 kHz	LSI RC osc. (128 kHz)	0.41	0.55	mA	
		f -f -	HSE crystal osc. (16 MHz)	4			
		f _{CPU} = f _{MASTER} = 16 MHz	HSE user ext. clock (16 MHz)	3.9	4.7		
	Supply current in run mode,		HSI RC osc. (16 MHz)	3.7	4.5		
	2 MHz	f _{CPU} = f _{MASTER} = 2 MHz	HSI RC osc. (16 MHz/8) ⁽²⁾	0.84	1.05		
		f _{CPU} = f _{MASTER} /	HSI RC osc. (16 MHz)	0.72	0.9		

⁽²⁾ Default clock configuration measured with all peripherals off.

Symbol	Parameter	Conditions		Тур	Max ⁽¹⁾	Unit
		128 = 125 kHz				
		$f_{CPU} = f_{MASTER}/$ 128 = 15.625 kHz	HSI RC osc. (16 MHz/8)	0.46	0.58	
		f _{CPU} = f _{MASTER} = 128 kHz	LSI RC osc. (128 kHz)	0.42	0.57	

⁽¹⁾ Data based on characterization results, not tested in production.

10.3.2.2 Total current consumption in wait mode

Table 24: Total current consumption in wait mode at V_{DD} = 5 V

Symbol	Parameter	Conditions		Тур	Max ⁽¹⁾	Unit
		f	HSE crystal osc. (16 MHz)	1.6		
		16 MHz	HSE user ext. clock (16 MHz)	1.1	1.3	
			HSI RC osc. (16 MHz)	0.89	1.1	
I _{DD(WFI)}	Supply current in	f _{CPU} = f _{MASTER} /128 = 125 kHz	HSI RC osc. (16 MHz)	0.7	0.88	mA
	wait mode	$f_{CPU} = f_{MASTER}/128 = $ 15.625 kHz $f_{CPU} = f_{MASTER} = $ HSI RC osc. (16 MH)	HSI RC osc. (16 MHz/8) ⁽²⁾	0.45	0.57	
			LSI RC osc. (128 kHz)	0.4	0.54	

⁽¹⁾ Data based on characterization results, not tested in production.

Table 25: Total current consumption in wait mode at V_{DD} = 3.3 V

Symbol	Parameter	Conditions	Тур	Max ⁽¹⁾	Unit	
I _{DD(WFI)}	Supply current in wait mode	f _{CPU} = f _{MASTER} = 16 MHz	HSE crystal osc. (16 MHz)	1.1		mA

⁽²⁾ Default clock configuration measured with all peripherals off.

⁽²⁾ Default clock configuration measured with all peripherals off.

Symbol	Parameter	Conditions	Conditions			Unit
			HSE user ext. clock (16 MHz)	1.1	1.3	
			HSI RC osc. (16 MHz)	0.89	1.1	
		f _{CPU} = f _{MASTER} / 128 = 125 kHz	HSI RC osc. (16 MHz)	0.7	0.88	
		f _{CPU} = f _{MASTER} / 128 = 15.625 kHz	HSI RC osc. (16 MHz/8) ⁽²⁾	0.45	0.57	
		f _{CPU} = f _{MASTER} = 128 kHz	LSI RC osc. (128 kHz)	0.4	0.54	

⁽¹⁾ Data based on characterization results, not tested in production.

10.3.2.3 Total current consumption in active halt mode

Table 26: Total current consumption in active halt mode at V_{DD} = 5 V

		Conditions				Max	Max	
Symbol	Parameter	Main voltage regulator (MVR) ⁽²⁾	Flash mode ⁽³⁾	Clock source	Тур	at 85 °C (1)	at 125 °C (1)	Unit
I _{DD(AH)}	Supply current in active halt mode	On	Operating mode	HSE crystal osc. (16 MHz)	1030			
I _{DD(AH)}	Supply current in active halt mode	On	Operating mode	LSI RC osc. (128 kHz)	200	260	300	μΑ
I _{DD(AH)}	Supply current in active halt mode	On	Power-down mode	HSE crystal osc. (16 MHz)	970			μΑ
I _{DD(AH)}	Supply current in active halt mode	On	Power-down mode	LSI RC osc. (128 kHz)	150	200	230	

⁽²⁾ Default clock configuration measured with all peripherals off.

		Conditions				Max	Max	
Symbol	Parameter	Main voltage regulator (MVR) ⁽²⁾	Flash mode ⁽³⁾	Clock source	Тур	°C		Unit
I _{DD(AH)}	Supply current in active halt mode	Off	Operating mode	LSI RC osc. (128 kHz)	66	85	110	
I _{DD(AH)}	Supply current in active halt mode	, Oii	Power-down mode	LSI RC osc. (128 kHz)	10	20	40	

⁽¹⁾ Data based on characterization results, not tested in production

Table 27: Total current consumption in active halt mode at V_{DD} = 3.3 V

		Conditions				May at	May of	
Symbol	Parameter	Main voltage regulator (MVR) ⁽²⁾	Flash mode ⁽³⁾	Clock source	Тур	Max at 85 °C (1)	Max at 125 °C	Unit
I _{DD(AH)}	Supply current in active halt mode	On	Operating mode	HSE crystal osc. (16 MHz)	550			μА
I _{DD(AH)}	Supply current in active halt		Operating mode	LSI RC osc. (128 kHz)	200	260	290	
I _{DD(AH)}	mode	On	Power-down	HSE crystal osc. (16 MHz)	970			
I _{DD(AH)}	Supply current		mode	LSI RC osc. (128 kHz)	150	200	230	μΑ
I _{DD(AH)}	in active halt mode		Operating mode	LSI RC osc.	66	80	105	
I _{DD(AH)}		Off	Power-down mode	(128 kHz)	10	18	35	

⁽¹⁾ Data based on characterization results, not tested in production

⁽²⁾ Configured by the REGAH bit in the CLK_ICKR register.

⁽³⁾ Configured by the AHALT bit in the FLASH_CR1 register.

 $^{^{(2)}}$ Configured by the REGAH bit in the CLK_ICKR register.

⁽³⁾ Configured by the AHALT bit in the FLASH_CR1 register.

10.3.2.4 Total current consumption in halt mode

Table 28: Total current consumption in halt mode at V_{DD} = 5 V

Symbol	Parameter	Conditions	Тур	Max at 85 °C ⁽¹⁾	Max at 125 °C ⁽¹⁾	Unit
L	Supply current in halt mode	Flash in operating mode, HSI clock after wakeup	63	75	105	μA
IDD(H)		Flash in power-down mode, HSI clock after wakeup	6.0	20	55	μΛ

⁽¹⁾ Data based on characterization results, not tested in production

Table 29: Total current consumption in halt mode at V_{DD} = 3.3 V

Symbol	Parameter	Conditions	Тур	Max at 85 °C ⁽¹⁾	Max at 125 °C ⁽¹⁾	Unit
	Supply current in halt mode	Flash in operating mode, HSI clock after wakeup	60	75	100	μA
IDD(H)		Flash in power-down mode, HSI clock after wakeup	4.5	17	30	μΛ

⁽¹⁾ Data based on characterization results, not tested in production

10.3.2.5 Low power mode wakeup times

Table 30: Wakeup times

Symbol	Parameter	Conditions			Тур	Max ⁽¹⁾	Unit			
t _{WU(WFI)}	Wakeup time from wait mode to run	0 to 16 MHz				See note ⁽²⁾				
*WU(WFI)	mode ⁽³⁾	f _{CPU} = f _{MASTE}	_R = 16 MHz		0.56					
	Wakeup time active halt mode to run mode ⁽³⁾	MVR voltage regulator on ⁽⁴⁾	Flash in operating mode ⁽⁵⁾	HSI (after wakeup)	1 ⁽⁶⁾	2 ⁽⁶⁾	μs			
t _{WU(AH)}	Wakeup time active halt mode to run mode ⁽³⁾	MVR voltage regulator on ⁽⁴⁾	Flash in power-down mode ⁽⁵⁾	HSI (after wakeup)	3 ⁽⁶⁾					

Symbol	Parameter	Conditions	Conditions			Max ⁽¹⁾	Unit
	Wakeup time active halt mode to run mode ⁽³⁾	MVR voltage regulator off ⁽⁴⁾	Flash in operating mode ⁽⁵⁾	HSI (after wakeup)	48 ⁽⁶⁾		
	Wakeup time active halt mode to run mode ⁽³⁾	MVR voltage regulator off ⁽⁴⁾	Flash in power-down mode ⁽⁵⁾	HSI (after wakeup)	50 ⁽⁶⁾		
	Wakeup time from	Flash in oper	ating mode ⁽⁵⁾		52		
t _{WU(H)}	halt mode to run mode ⁽³⁾	(5)			54		

⁽¹⁾ Data guaranteed by design, not tested in production.

10.3.2.6 Total current consumption and timing in forced reset state

Table 31: Total current consumption and timing in forced reset state

Symbol	Parameter	Conditions	Тур	Max ⁽¹⁾	Unit
I _{DD(R)}	Supply current in reset	V _{DD} = 5 V	400		μA
	state ⁽²⁾	V _{DD} = 3.3 V	300		μΛ
t _{RESETBL}	Reset pin release to vector fetch			150	μs

⁽¹⁾ Data guaranteed by design, not tested in production.

10.3.2.7 Current consumption of on-chip peripherals

Subject to general operating conditions for V_{DD} and T_A .

 $^{^{(2)}}$ t_{WU(WFI)} = 2 x 1/f_{master} + 6 x 1/f_{CPU}

⁽³⁾ Measured from interrupt event to interrupt vector fetch.

⁽⁴⁾ Configured by the REGAH bit in the CLK ICKR register.

⁽⁵⁾ Configured by the AHALT bit in the FLASH CR1 register.

⁽⁶⁾ Plus 1 LSI clock depending on synchronization.

 $^{^{(2)}}$ Characterized with all I/Os tied to V_{SS} .

HSI internal RC/ $f_{CPU} = f_{MASTER} = 16 \text{ MHz}, V_{DD} = 5 \text{ V}$

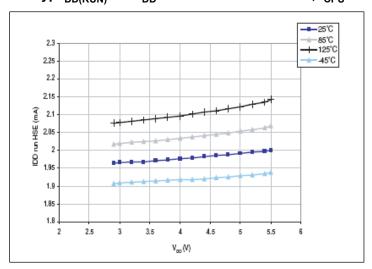
Symbol	Parameter	Тур.	Unit
I _{DD(TIM1)}	TIM1 supply current ⁽¹⁾	210	μA
I _{DD(TIM5)}	TIM5 supply current ⁽¹⁾	130	
I _{DD(TIM6)}	TIM6 timer supply current ⁽¹⁾	50	
I _{DD(UART1)}	UART1 supply current ⁽²⁾	120	
I _{DD(SPI)}	SPI supply current ⁽²⁾	45	
I _{DD(I} ² _{C)}	I ² C supply current ⁽²⁾	65	
I _{DD(ADC1)}	ADC1 supply current when converting ⁽³⁾	1000	

 $^{^{(1)}}$ Data based on a differential I_{DD} measurement between reset configuration and timer counter running at 16 MHz. No IC/OC programmed (no I/O pads toggling). Not tested in production.

10.3.2.8 Current consumption curves

The following figures show typical current consumption measured with code executing in RAM.

Figure 11: Typ $I_{DD(RUN)}$ vs. V_{DD} HSE user external clock, f_{CPU} = 16 MHz



⁽²⁾ Data based on a differential I_{DD} measurement between the on-chip peripheral when kept under reset and not clocked and the on-chip peripheral when clocked and not kept under reset. No I/O pads toggling. Not tested in production.

⁽³⁾ Data based on a differential I_{DD} measurement between reset configuration and continuous A/D conversions. Not tested in production.

Figure 12: Typ $I_{DD(RUN)}$ vs. f_{CPU} HSE user external clock, V_{DD} = 5 V

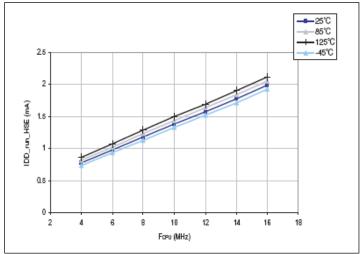


Figure 13: Typ $I_{DD(RUN)}$ vs. V_{DD} HSI RC osc, f_{CPU} = 16 MHz

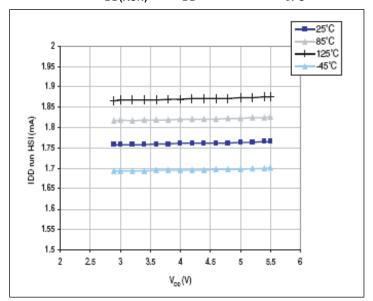


Figure 14: Typ $I_{DD(WFI)}$ vs. V_{DD} HSE user external clock, f_{CPU} = 16 MHz

Figure 15: Typ $I_{DD(WFI)}$ vs. f_{CPU} HSE user external clock, V_{DD} = 5 V

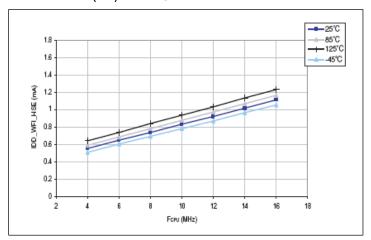
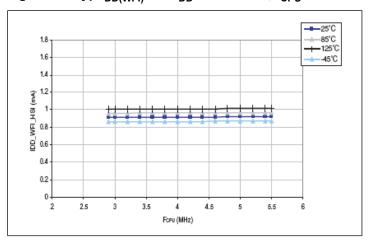


Figure 16: Typ $I_{DD(WFI)}$ vs. V_{DD} HSI RC osc, f_{CPU} = 16 MHz



10.3.3 External clock sources and timing characteristics

HSE user external clock

Subject to general operating conditions for V_{DD} and T_A .

Table 33: HSE user external clock characteristics

Symbol	Parameter	Conditions	Min	Max	Unit
f _{HSE_ext}	User external clock source frequency		0	16	MHz
V _{HSEH} (1)	OSCIN input pin high level voltage		0.7 x V _{DD}	V _{DD} + 0.3 V	V
V _{HSEL} (1)	OSCIN input pin low level voltage		V _{SS}	0.3 x V _{DD}	V
I _{LEAK_HSE}	OSCIN input leakage current	$V_{SS} < V_{IN} < V_{DD}$	-1	+1	μΑ

⁽¹⁾ Data based on characterization results, not tested in production.

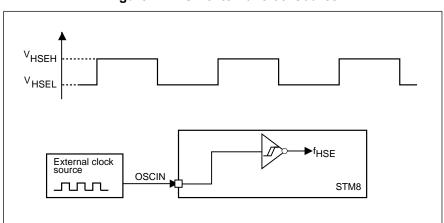


Figure 17: HSE external clocksource

HSE crystal/ceramic resonator oscillator

The HSE clock can be supplied with a 1 to 16 MHz crystal/ceramic resonator oscillator. All the information given in this paragraph is based on characterization results with specified typical external components. In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and start-up stabilization time. Refer to the crystal resonator manufacturer for more details (frequency, package, accuracy...).

 Symbol
 Parameter
 Conditions
 Min
 Typ
 Max
 Unit

 f_{HSE}
 External high speed oscillator frequency
 1
 16
 MHz

Table 34: HSE oscillator characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _F	Feedback resistor			220		kΩ
C ⁽¹⁾	Recommended load capacitance ⁽²⁾				20	pF
I _{DD(HSE)}	HSE oscillator power consumption	C = 20 pF, f _{OSC} = 16 MHz			6 (startup) 1.6 (stabilized) ⁽³⁾	- mA
		C = 10 pF, f _{OSC} =16 MHz			6 (startup) 1.2 (stabilized) ⁽³⁾	111/4
g _m	Oscillator transconductance		5			mA/V
t _{SU(HSE)} (4)	Startup time	V _{DD} is stabilized		1		ms

⁽¹⁾ C is approximately equivalent to 2 x crystal Cload.

 $^{^{(4)}}$ $t_{SU(HSE)}$ is the start-up time measured from the moment it is enabled (by software) to a stabilized 16 MHz oscillation is reached. This value is measured for a standard crystal resonator and it can vary significantly with the crystal manufacturer.

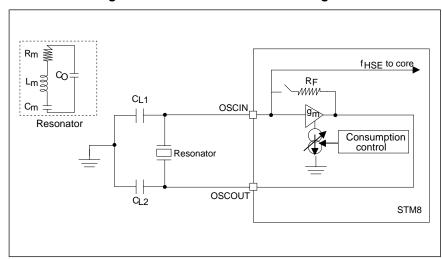


Figure 18: HSE oscillator circuit diagram

HSE oscillator critical g _m equation

$$g_{mcrit}$$
= $(2 \times \Pi \times f_{HSE})^2 \times R_m (2Co + C)^2$

 $^{^{(2)}}$ The oscillator selection can be optimized in terms of supply current using a high quality resonator with small $R_{\rm m}$ value. Refer to crystal manufacturer for more details

⁽³⁾ Data based on characterization results, not tested in production.

R_m: Notional resistance (see crystal specification)

L_m: Notional inductance (see crystal specification)

C_m: Notional capacitance (see crystal specification)

Co: Shunt capacitance (see crystal specification)

 $C_{L1} = C_{L2} = C$: Grounded external capacitance

 $g_m >> g_{mcrit}$

10.3.4 Internal clock sources and timing characteristics

Subject to general operating conditions for V_{DD} and T_A .

High speed internal RC oscillator (HSI)

Table 35: HSI oscillator characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
f _{HSI}	Frequency			16		MHz
ACC _{HSI}	Accuracy of HSI oscillator	User-trimmed with CLK_HSITRIMR register for given V _{DD} and T _A conditions ⁽¹⁾			1.0 ⁽³⁾	
	Accuracy of HSI	$V_{DD} = 5 \text{ V}, T_A = 25^{\circ} \text{C}^{(2)}$	-1.0		1.0	%
	oscillator (factory calibrated)	V _{DD} = 5 V, 25 °C ≤ T _A ≤ 85 °C	-2.0		2.0	
		2.95 ≤ V _{DD} ≤ 5.5 V,-40 °C ≤ T _A ≤ 125 °C	-3.0 ⁽²⁾		3.0 ⁽²⁾	
t _{su(HSI)}	HSI oscillator wakeup time including calibration				1.0 ⁽³⁾	μs
I _{DD(HSI)}	HSI oscillator power consumption			170	250 ⁽²⁾	μΑ

⁽¹⁾ Refer to application note.

 $^{^{\}left(2\right) }$ Data based on characterization results, not tested in production.

⁽³⁾ Guaranteed by design, not tested in production.

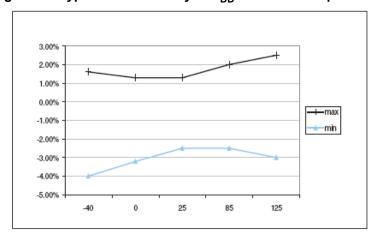
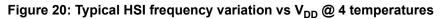
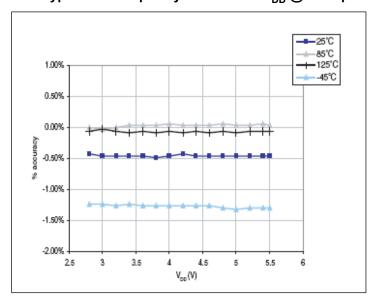


Figure 19: Typical HSI accuracy at V_{DD} = 5 V vs 5 temperatures





Low speed internal RC oscillator (LSI)

Subject to general operating conditions for $\rm V_{\rm DD}$ and $\rm T_{\rm A}.$

Table 36: LSI oscillator characteristics

Symbol	Parameter	Min	Тур	Max	Unit
f _{LSI}	Frequency	110	128	150	kHz
t _{su(LSI)}	LSI oscillator wake-up time			7	μs
I _{DD(LSI)}	LSI oscillator power consumption		5		μΑ

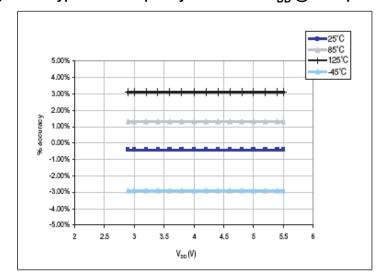


Figure 21: Typical LSI frequency variation vs V_{DD} @ 4 temperatures

10.3.5 Memory characteristics

RAM and hardware registers

Table 37: RAM and hardware registers

Symbol	Parameter	Conditions	Min	Unit
V_{RM}	Data retention mode ⁽¹⁾	Halt mode (or reset)	V _{IT-max} (2)	V

⁽¹⁾ Minimum supply voltage without losing data stored in RAM (in halt mode or under reset) or in hardware registers (only in halt mode). Guaranteed by design, not tested in production.

Flash program memory/data EEPROM memory

Table 38: Flash program memory/data EEPROM memory

Symbol	Parameter	Conditions	Min ⁽¹⁾	Тур	Max	Unit
V _{DD}	Operating voltage (all modes, execution/ write/erase)	f _{CPU} ≤ 16 MHz	2.95		5.5	V
t _{prog}	Standard programming time (including erase) for byte/word/block (1 byte/ 4 bytes/64 bytes)			6	6.6	ms
	Fast programming time for			3	3.33	

 $^{^{(2)}}$ Refer to the Operating conditions section for the value of $V_{\text{IT-max}}$

Symbol	Parameter	Conditions	Min ⁽¹⁾	Тур	Max	Unit
	1 block (64 bytes)					
t _{erase}	Erase time for 1 block (64 bytes)			3	3.33	
N _{RW}	Erase/write cycles ⁽²⁾ (program memory)	T _A = +85 °C	10 k			cycles
	Erase/write cycles (data memory) ⁽²⁾	T _A = +125 °C	300 k	1 M		Cycles
t _{RET}	Data retention (program and data memory) after 10k erase/write cycles at T _A = +55 °C	T _{RET} = 55°C	20			voore
	Data retention (data memory) after 300k erase/write cycles at T _A = +125 °C	T _{RET} = 85°C	1			years
I _{DD}	Supply current (Flash programming or erasing for 1 to 128 bytes)			2		mA

⁽¹⁾ Data based on characterization results, not tested in production.

10.3.6 I/O port pin characteristics

General characteristics

Subject to general operating conditions for V_{DD} and T_A unless otherwise specified. All unused pins must be kept at a fixed voltage: using the output mode of the I/O for example or an external pull-up or pull-down resistor.

Table 39: I/O static characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{IL}	Input low level voltage	V _{DD} = 5 V	-0.3 V		0.3 x V _{DD}	V

⁽²⁾ The physical granularity of the memory is 4 bytes, so cycling is performed on 4 bytes even when a write/erase operation addresses a single byte.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{IH}	Input high level voltage		0.7 x V _{DD}		V _{DD} + 0.3	
V _{hys}	Hysteresis ⁽¹⁾			700		mV
R _{pu}	Pull-up resistor	V_{DD} = 5 V, V_{IN} = V_{SS}	30	45	60	kΩ
t _R , t _F	Rise and fall time (10 % - 90 %)	Fast I/Os Load = 50 pF			20 ⁽²⁾	
		Standard and high sink I/Os Load = 50 pF			125 ⁽²⁾	ns
I _{lkg}	Digital input leakage current	$V_{SS} \le V_{IN} \le V_{DD}$			±1 ⁽²⁾	μΑ
I _{lkg ana}	Analog input leakage current	$V_{SS} \le V_{IN} \le V_{DD}$			±250 ⁽²⁾	nA
I _{lkg(inj)}	Leakage current in adjacent I/O	Injection current ±4 mA			±1 ⁽²⁾	μΑ

 $^{^{(1)}}$ Hysteresis voltage between Schmitt trigger switching levels. Based on characterization results, not tested in production.

 $^{^{(2)}\!\}mathsf{Data}$ based on characterisation results, not tested in production.

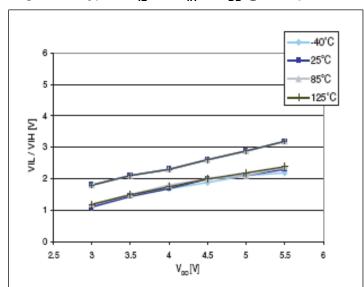


Figure 22: Typical $V_{\rm IL}$ and $V_{\rm IH}$ vs $V_{\rm DD}$ @ 4 temperatures

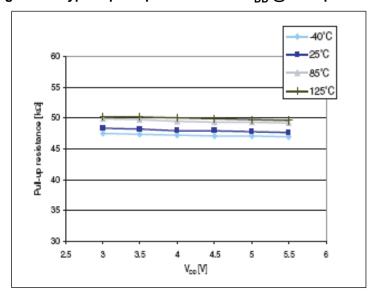


Figure 23: Typical pull-up resistance vs V_{DD} @ 4 temperatures



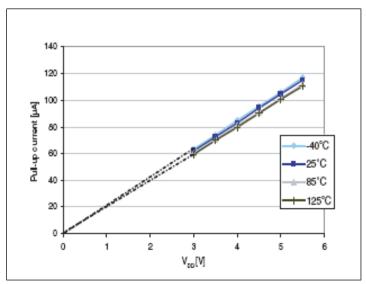


Table 40: Output driving current (standard ports)

Symbol	Parameter	Conditions	Min	Max	Unit
V	Output low level with 8 pins sunk	I _{IO} = 10 mA, V _{DD} = 5 V		2.0	
V _{OL}	Output low level with 4 pins sunk	I _{IO} = 4 mA, V _{DD} = 3.3 V		1.0 ⁽¹⁾	V
V _{OH}	Output high level with 8 pins sourced	I _{IO} = 10 mA, V _{DD} = 5 V	2.8		

Symbol	Parameter	Conditions	Min	Max	Unit
	Output high level with 4 pins sourced	I _{IO} = 4 mA, V _{DD} = 3.3 V	2.1 ⁽¹⁾		

⁽¹⁾ Data based on characterization results, not tested in production

Table 41: Output driving current (true open drain ports)

Symbol	Parameter	Conditions	Max	Unit
V _{OL}	Output low level with 2 pins sunk	I _{IO} = 10 mA, V _{DD} = 5 V	1 .0	
V _{OL}	Output low level with 2 pins sunk	I _{IO} = 10 mA, V _{DD} = 3.3 V	1.5 ⁽¹⁾	V
V _{OL}	Output low level with 2 pins sunk	I _{IO} = 20 mA, V _{DD} = 5 V	2.0 ⁽¹⁾	

⁽¹⁾ Data based on characterization results, not tested in production

Table 42: Output driving current (high sink ports)

Symbol	Parameter	Conditions	Min	Max	Unit
V _{OL}	Output low level with 8 pins sunk	I _{IO} = 10 mA, V _{DD} = 5 V		0.8	V
V _{OL}	Output low level with 4 pins sunk	I _{IO} = 10 mA, V _{DD} = 3.3 V		1.0 ⁽¹⁾	
	Output low level with 4 pins sunk	I _{IO} = 20 mA, V _{DD} = 5 V		1.5 ⁽¹⁾	
V _{OH}	Output high level with 8 pins sourced	I _{IO} = 10 mA, V _{DD} = 5 V	4.0		V
	Output high level with 4 pins sourced	I _{IO} = 10 mA, V _{DD} = 3.3 V	2.1 ⁽¹⁾		
	Output high level with 4 pins sourced	I _{IO} = 20 mA, V _{DD} = 5 V	3.3 ⁽¹⁾		

⁽¹⁾ Data based on characterization results, not tested in production

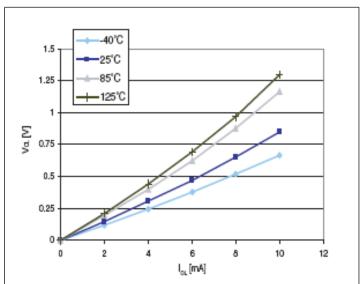
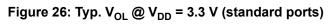
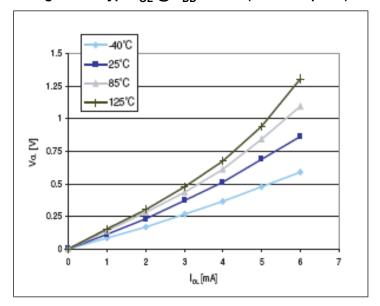


Figure 25: Typ. $V_{OL} @ V_{DD} = 5 V$ (standard ports)





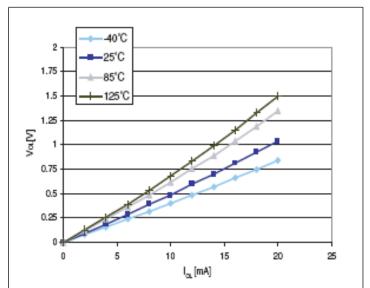
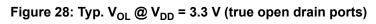
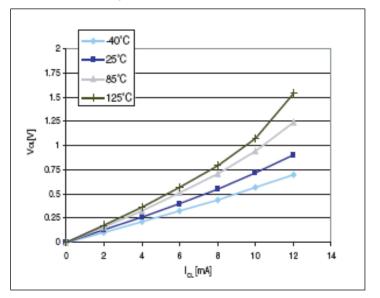


Figure 27: Typ. $V_{OL} @ V_{DD} = 5 V$ (true open drain ports)





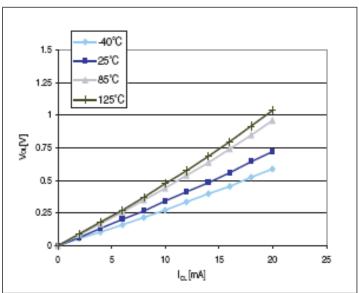
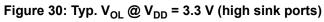
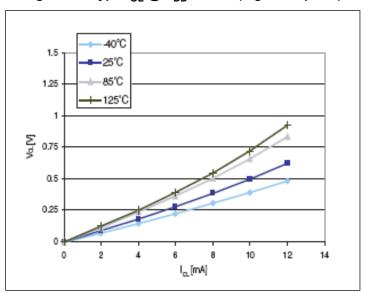


Figure 29: Typ. $V_{OL} @ V_{DD} = 5 V$ (high sink ports)





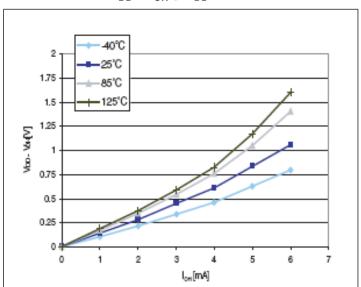
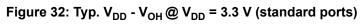
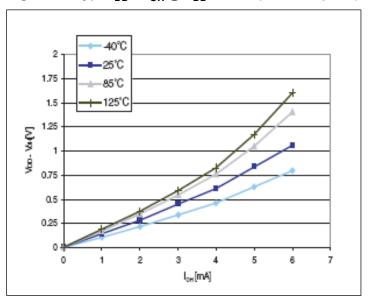


Figure 31: Typ. V_{DD} - V_{OH} @ V_{DD} = 5 V (standard ports)





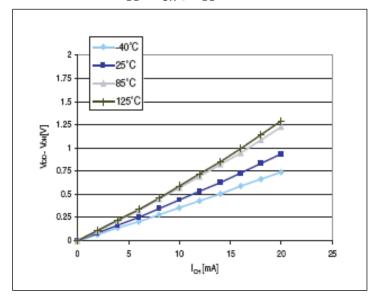
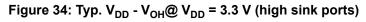
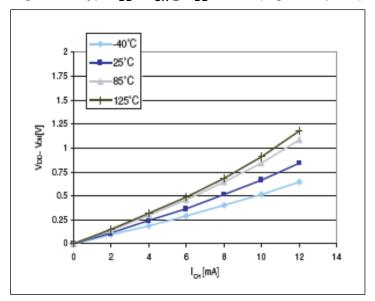


Figure 33: Typ. V_{DD} - V_{OH} @ V_{DD} = 5 V (high sink ports)





10.3.7 Reset pin characteristics

Subject to general operating conditions for V_{DD} and T_{A} unless otherwise specified.

Table 43: NRST pin characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{IL(NRST)}	NRST input low level voltage ⁽¹⁾		-0.3 V		0.3 x V _{DD}	V

Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
V _{IH(NRST)}	NRST input high level voltage ⁽¹⁾	I _{OL} =2 mA	0.7 x V _{DD}		V _{DD} + 0.3	
V _{OL(NRST)}	NRST output low level voltage ⁽¹⁾				0.5	
R _{PU(NRST)}	NRST pull-up resistor ⁽²⁾		30	40	60	kΩ
t _{I FP(NRST)}	NRST input filtered pulse ⁽³⁾				75	ns
t _{IN FP(NRST)}	NRST input not filtered pulse ⁽³⁾		500			1115
t _{OP(NRST)}	NRST output pulse (3)		20			μs

 $^{^{\}left(1\right)}$ Data based on characterization results, not tested in production.

⁽³⁾ Data guaranteed by design, not tested in production.

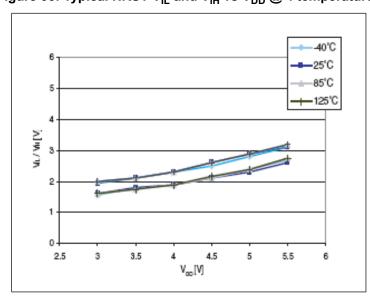


Figure 35: Typical NRST $\rm V_{IL}$ and $\rm V_{IH}$ vs $\rm V_{DD}$ @ 4 temperatures

 $^{^{(2)}}$ The R_{PU} pull-up equivalent resistor is based on a resistive transistor

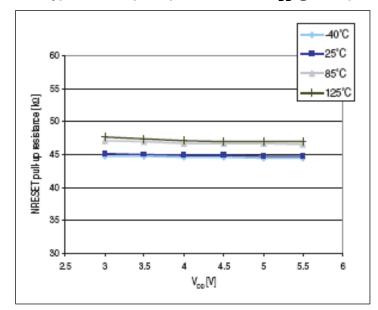
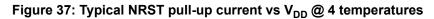
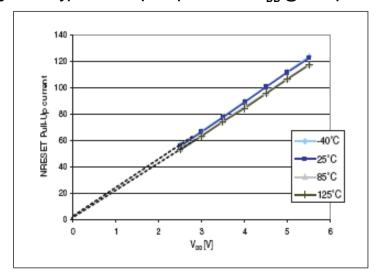


Figure 36: Typical NRST pull-up resistance vs V_{DD} @ 4 temperatures





The reset network shown in the following figure protects the device against parasitic resets. The user must ensure that the level on the NRST pin can go below the $V_{\rm IL}$ max. level specified in the I/O port pin characteristics section. Otherwise the reset is not taken into account internally.

External reset circuit
(optional)

RPU

RPU

Filter Internal reset

Figure 38: Recommended reset pin protection

10.3.8 SPI serial peripheral interface

Unless otherwise specified, the parameters given in the following table are derived from tests performed under ambient temperature, f_{MASTER} frequency and V_{DD} supply voltage conditions. $t_{MASTER} = 1/f_{MASTER}$.

Refer to I/O port characteristics for more details on the input/output alternate function characteristics (NSS, SCK, MOSI, MISO).

Symbol	Parameter	Conditions ⁽¹⁾	Min	Max	Unit
f _{SCK} 1/	SPI clock	Master mode	0	8	MHz
t _{c(SCK)}	frequency				1711 12
f _{SCK} 1/	f _{SCK} 1/ t _{c(SCK)}	SPI clock frequency	0	7 ⁽²⁾	MHz
t _{c(SCK)}				,	1711 12
t _{r(SCK)}	SPI clock rise and	Capacitive load: C = 30 pF		25	
t _{f(SCK)}	fall time			25	
t _{su(NSS)} (3)	NSS setup time	Slave mode	4 x		
			t _{MASTER}		
t _{h(NSS)} (3)	NSS hold time	Slave mode	70		ns
t _{w(SCKH)} (3)	SCK high and low	Master mode	t _{SCK} /	t _{SCK} /	
t _{w(SCKL)} (3)	time		2 - 15	2 +15	
t _{su(MI)} (3)	Data input setup	Master mode	5		
t _{su(SI)} (3)	time	Slave mode	5		

Table 44: SPI characteristics

Symbol	Parameter	Conditions ⁽¹⁾	Min	Мах	Unit
t _{h(MI)} (3)	Data input hold	Master mode	7		
t _{h(SI)} (3)	time	Slave mode	10		
t _{a(SO)} (3) (4)	Data output	Slave mode		3 x	
	access time			t _{MASTER}	
t _{dis(SO)} (3) (5)	Data output disable time	Slave mode	25		
t _{v(SO)} (3)	Data output valid time	Slave mode (after enable edge)		65 ⁽²⁾	
t _{v(MO)} (3)	Data output valid time	Master mode (after enable edge)		30	
t _{h(SO)} (3)	Data output hold time	Slave mode (after enable edge)	27 ⁽²⁾		
t _{h(MO)} (3)	Data output hold time	Master mode (after enable edge)	11 ⁽²⁾		

⁽¹⁾ Parameters are given by selecting 10 MHz I/O output frequency.

⁽²⁾ Data characterization in progress.

 $^{^{(3)}}$ Values based on design simulation and/or characterization results, and not tested in production.

⁽⁴⁾ Min time is for the minimum time to drive the output and the max time is for the maximum time to validate the data.

 $^{^{(5)}}$ Min time is for the minimum time to invalidate the output and the max time is for the maximum time to put the data in Hi-Z.

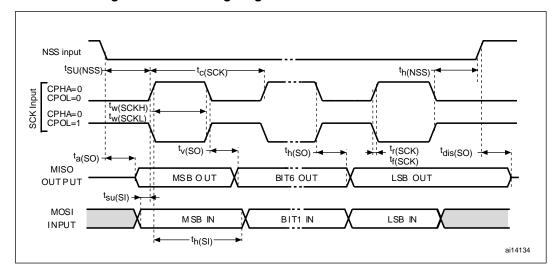
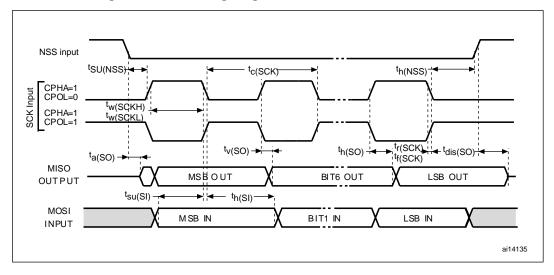


Figure 39: SPI timing diagram - slave mode and CPHA = 0





1. Measurement points are made at CMOS levels: 0.3 VDD and 0.7 VDD.

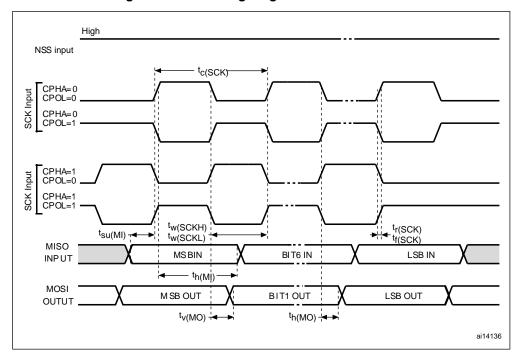


Figure 41: SPI timing diagram - master mode⁽¹⁾

1. Measurement points are made at CMOS levels: 0.3 VDD and 0.7 VDD.

10.3.9 I²C interface characteristics

Table 45: I²C characteristics

Symbol	Parameter	Standard mode I	Standard mode I ² C		Fast mode I ² C ⁽¹⁾	
		Min ⁽²⁾	Max ⁽²⁾	Min ⁽²⁾	Max ⁽²⁾	
t _{w(SCLL)}	SCL clock low time	4.7		1.3		
t _{w(SCLH)}	SCL clock high time	4.0		0.6		μs
t _{su(SDA)}	SDA setup time	250		100		
t _{h(SDA)}	SDA data hold time	0 ⁽³⁾		0 ⁽⁴⁾	900 ⁽³⁾	
t _{r(SDA)}	SDA and SCL rise time		1000		300	ns
$t_{f(SDA)}$ $t_{f(SCL)}$	SDA and SCL fall time		300		300	
t _{h(STA)}	START condition hold time	4.0		0.6		116
t _{su(STA)}	Repeated START condition setup time	4.7		0.6		μs

Symbol	Parameter	Standard mode I ² C		Standard mode I ² C Fast mode I ² C ⁽¹⁾		de I ² C ⁽¹⁾	Unit
		Min ⁽²⁾	Max ⁽²⁾	Min ⁽²⁾	Max ⁽²⁾		
t _{su(STO)}	STOP condition setup time	4.0		0.6			
t _{w(STO:STA)}	STOP to START condition time (bus free)	4.7		1.3		μs	
C _b	Capacitive load for each bus line		400		400	pF	

 $^{^{(1)}}$ f_{MASTER}, must be at least 8 MHz to achieve max fast I 2 C speed (400kHz)

 $^{^{(4)}}$ The device must internally provide a hold time of at least 300 ns for the SDA signal in order to bridge the undefined region of the falling edge of SCL

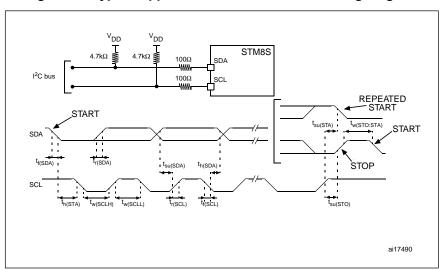


Figure 42: Typical application with I²C bus and timing diagram

1. Measurement points are made at CMOS levels: 0.3 x VDD and 0.7 x VDD.

10.3.10 10-bit ADC characteristics

Subject to general operating conditions for V_{DD} , f_{MASTER} , and T_A unless otherwise specified.

Table 46: ADC characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
f _{ADC}	ADC clock frequency	V _{DD} =2.95 to 5.5 V	1		4	MHz

⁽²⁾ Data based on standard I²C protocol requirement, not tested in production

⁽³⁾ The maximum hold time of the start condition has only to be met if the interface does not stretch the low time

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
		V _{DD} =4.5 to 5.5 V	1		6	
V _{AIN}	Conversion voltage range ⁽¹⁾		V _{SS}		V_{DD}	٧
V _{BGREF}	Internal bandgap reference voltage	V _{DD} =2.95 to 5.5 V	1.19	1.22	1.25	V
C _{ADC}	Internal sample and hold capacitor			3		pF
t _S (1)	Minimum sampling time	f _{ADC} = 4 MHz		0.75		μs
		f _{ADC} = 6 MHz		0.5		
t _{STAB}	Wake-up time from standby			7		μs
t _{CONV}	Minimum total conversion	f _{ADC} = 4 MHz	3.5			μs
	time (including sampling time, 10-bit resolution)	f _{ADC} = 6 MHz	2.33			μs
			14			1/f _{ADC}

 $^{^{(1)}}$ During the sample time the input capacitance C_{AIN} (3 pF max) can be charged/discharged by the external source. The internal resistance of the analog source must allow the capacitance to reach its final voltage level within $t_{S_{\cdot}}$ After the end of the sample time $t_{S_{\cdot}}$ changes of the analog input voltage have no effect on the conversion result. Values for the sample clock t_{S} depend on programming.

Table 47: ADC accuracy with $\rm R_{AIN}\,{<}\,10~k\Omega$, $\rm V_{DD}{=}\,5~V$

Symbol	Parameter	Conditions	Тур	Max ⁽¹⁾	Unit
E _T	Total unadjusted error ⁽²⁾	f _{ADC} = 2 MHz	1.6	3.5	LSB
		f _{ADC} = 4 MHz	2.2	4	
		f _{ADC} = 6 MHz	2.4	4.5	
E _O	Offset error ⁽²⁾	f _{ADC} = 2 MHz	1.1	2.5	
		f _{ADC} = 4 MHz	1.5	3	
		f _{ADC} = 6 MHz	1.8	3	
E _G	Gain error ⁽²⁾	f _{ADC} = 2 MHz	1.5	3	
		f _{ADC} = 4 MHz	2.1	3	
		f _{ADC} = 6 MHz	2.2	4	
E _D	Differential linearity error ⁽²⁾	f _{ADC} = 2 MHz	0.7	1.5	
		f _{ADC} = 4 MHz	0.7	1.5	

Symbol	Parameter	Conditions	Тур	Max ⁽¹⁾	Unit
		f _{ADC} = 6 MHz	0.7	1.5	
E _L	Integral linearity error ⁽²⁾	f _{ADC} = 2 MHz	0.6	1.5	
		f _{ADC} = 4 MHz	0.8	2	
		f _{ADC} = 6 MHz	0.8	2	

⁽¹⁾ Data based on characterisation results, not tested in production.

Table 48: ADC accuracy with R_{AIN} < 10 k Ω R_{AIN} , V_{DD} = 3.3 V

Symbol	Parameter	Conditions	Тур	Max ⁽¹⁾	Unit
E _T	Total unadjusted error	f _{ADC} = 2 MHz	1.6	3.5	LSB
		f _{ADC} = 4 MHz	1.9	4	
E _O	Offset error	f _{ADC} = 2 MHz	1	2.5	
		f _{ADC} = 4 MHz	1.5	2.5	
E _G	Gain error	f _{ADC} = 2 MHz	1.3	3	
		f _{ADC} = 4 MHz	2	3	
E _D	Differential linearity error	f _{ADC} = 2 MHz	0.7	1	
		f _{ADC} = 4 MHz	0.7	1.5	
E _L	Integral linearity error	f _{ADC} = 2 MHz	0.6	1.5	
		f _{ADC} = 4 MHz	0.8	2	

⁽¹⁾ Data based on characterisation results, not tested in production.

⁽²⁾ ADC accuracy vs. negative injection current: Injecting negative current on any of the analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to standard analog pins which may potentially inject negative current. Any positive injection current within the limits specified for $I_{INJ(PIN)}$ and $\Sigma I_{INJ(PIN)}$ in the I/O port pin characteristics section does not affect the ADC accuracy.

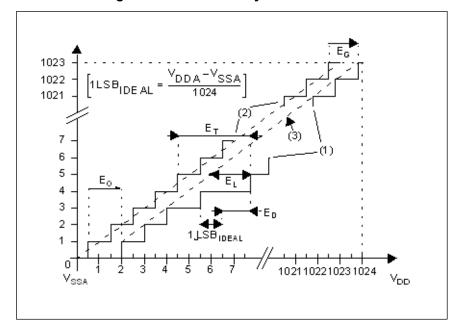


Figure 43: ADC accuracy characteristics

- 1. Example of an actual transfer curve.
- 2. The ideal transfer curve
- 3. End point correlation line

 E_T = Total unadjusted error: maximum deviation between the actual and the ideal transfer curves.

 E_0 = Offset error: deviation between the first actual transition and the first ideal one.

 E_G = Gain error: deviation between the last ideal transition and the last actual one.

 $E_{\rm D}$ = Differential linearity error: maximum deviation between actual steps and the ideal one.

 E_L = Integral linearity error: maximum deviation between any actual transition and the end point correlation line.

VAIN RAIN
AINX
VT
0.6 V

CAIN
CAIN
CADC

Figure 44: Typical application with ADC

57

10.3.11 EMC characteristics

Susceptibility tests are performed on a sample basis during product characterization.

10.3.11.1 Functional EMS (electromagnetic susceptibility)

While executing a simple application (toggling 2 LEDs through I/O ports), the product is stressed by two electromagnetic events until a failure occurs (indicated by the LEDs).

- FESD: Functional electrostatic discharge (positive and negative) is applied on all pins of the device until a functional disturbance occurs. This test conforms with the IEC 61000-4-2 standard.
- FTB: A burst of fast transient voltage (positive and negative) is applied to V_{DD} and V_{SS} through a 100 pF capacitor, until a functional disturbance occurs. This test conforms with the IEC 61000-4-4 standard.

A device reset allows normal operations to be resumed. The test results are given in the table below based on the EMS levels and classes defined in application note AN1709 (EMC design guide for STMicrocontrollers).

10.3.11.2 Designing hardened software to avoid noise problems

EMC characterization and optimization are performed at component level with a typical application environment and simplified MCU software. It should be noted that good EMC performance is highly dependent on the user application and the software in particular.

Therefore it is recommended that the user applies EMC software optimization and prequalification tests in relation with the EMC level requested for his application.

Prequalification trials

Most of the common failures (unexpected reset and program counter corruption) can be recovered by applying a low state on the NRST pin or the oscillator pins for 1 second.

To complete these trials, ESD stress can be applied directly on the device, over the range of specification values. When unexpected behavior is detected, the software can be hardened to prevent unrecoverable errors occurring. See application note AN1015 (Software techniques for improving microcontroller EMC performance).

Table 49: EMS data

Symbol	Parameter	Conditions	Level/ class
V _{FESD}	Voltage limits to be applied on any I/O pin to induce a functional disturbance	V_{DD} = 3.3 V, T_A = 25 °C, f_{MASTER} = 16 MHz (HSI clock), conforming to IEC 61000-4-2	2/B ⁽¹⁾
V _{EFTB}	Fast transient voltage burst limits to be applied through 100 pF on V _{DD} and V _{SS} pins to induce a functional disturbance	V_{DD} = 3.3 V, T_A = 25 °C , f_{MASTER} = 16 MHz (HSI clock),conforming to IEC 61000-4-4	4/A ⁽¹⁾

⁽¹⁾Data obtained with HSI clock configuration, after applying HW recommendations described in AN2860 (EMC guidelines for STM8S microcontrollers).

10.3.11.3 Electromagnetic interference (EMI)

Based on a simple application running on the product (toggling 2 LEDs through the I/O ports), the product is monitored in terms of emission. This emission test is in line with the norm SAE IEC 61967-2 which specifies the board and the loading of each pin.

Conditions Max f_{HSE}/f_{CPU} (1) Symbol Parameter Unit General Monitored 16 MHz/ 16 MHz/ conditions frequency band 16 MHz 8 MHz Peak level $V_{DD} = 5 V$ 0.1 MHz to 5 5 T_A = 25 °C 30 MHz LQFP32 package 30 MHz to 4 5 dBµV Conforming to 130 MHz SAE IEC S_{EMI} 61967-2 130 MHz to 5 5 1 GHz SAE EMI 2.5 SAE EMI level 2.5 level

Table 50: EMI data

10.3.11.4 Absolute maximum ratings (electrical sensitivity)

Based on three different tests (ESD, DLU and LU) using specific measurement methods, the product is stressed to determine its performance in terms of electrical sensitivity. For more details, refer to the application note AN1181.

10.3.11.5 Electrostatic discharge (ESD)

Electrostatic discharges (a positive then a negative pulse separated by 1 second) are applied to the pins of each sample according to each pin combination. The sample size depends on the number of supply pins in the device (3 parts*(n+1) supply pin). One model can be simulated:

⁽¹⁾ Data based on characterisation results, not tested in production.

Human body model. This test conforms to the JESD22-A114A/A115A standard. For more details, refer to the application note AN1181.

Maximum Unit Symbol **Conditions** Ratings Class value⁽¹⁾ V_{ESD(HBM)} Electrostatic discharge $T_A = 25$ °C, conforming to 4000 JESD22-A114 Α voltage (Human body model) $V_{ESD(CDM)}$ Electrostatic discharge T_△ LQFP32 package = IV 1000 voltage 25°C, conforming to SD22-C101 (Charge device model)

Table 51: ESD absolute maximum ratings

10.3.11.6 Static latch-up

Two complementary static tests are required on six parts to assess the latch-up performance:

- A supply overvoltage (applied to each power supply pin)
- A current injection (applied to each input, output and configurable I/O pin) are performed on each sample.

This test conforms to the EIA/JESD 78 IC latch-up standard. For more details, refer to the application note AN1181.

 $\begin{array}{|c|c|c|c|c|c|} \hline \textbf{Symbol} & \textbf{Parameter} & \textbf{Conditions} & \textbf{Class}^{(1)} \\ \hline \textbf{LU} & \textbf{Static latch-up class} & T_{A} = 25 \, ^{\circ}\text{C} & A \\ \hline T_{A} = 85 \, ^{\circ}\text{C} & A \\ \hline T_{A} = 125 \, ^{\circ}\text{C} & A \\ \hline \end{array}$

Table 52: Electrical sensitivities

⁽¹⁾ Data based on characterization results, not tested in production

⁽¹⁾ Class description: A Class is an STMicroelectronics internal specification. All its limits are higher than the JEDEC specifications, that means when a device belongs to class A it exceeds the JEDEC standard. B class strictly covers all the JEDEC criteria (international standard).

11 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

11.1 32-pin LQFP package mechanical data

Figure 45: 32-pin low profile quad flat package (7 x 7)

Table 53: 32-pin low profile quad flat package mechanical data

Dim.	mm			inches ⁽¹⁾		
	Min	Тур	Max	Min	Тур	Max
А			1.600			0.0630
A1	0.050		0.150	0.0020		0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.300	0.370	0.450	0.0118	0.0146	0.0177
С	0.090		0.200	0.0035		0.0079
D	8.800	9.000	9.200	0.3465	0.3543	0.3622
D1	6.800	7.000	7.200	0.2677	0.2756	0.2835

Dim.	mm			inches ⁽¹⁾		
	Min	Тур	Мах	Min	Тур	Max
D3		5.600			0.2205	
E	8.800	9.000	9.200	0.3465	0.3543	0.3622
E1	6.800	7.000	7.200	0.2677	0.2756	0.2835
E3		5.600			0.2205	
е		0.800			0.0315	
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1		1.000			0.0394	
k	0.0°	3.5°	7.0°	0.0°	3.5°	7.0°
ссс			0.100			0.0039

 $^{^{(1)}}$ Values in inches are converted from mm and rounded to 4 decimal digits

11.2 32-lead UFQFPN package mechanical data

<u>D</u>-**A** PIN 1 IDENTIFIER LASER MARKING AREA В // 0.100 C 0.100 (4X) 0.100(M) C A B 0.050(M) C DETAIL Y C0.300x45* ⊕ 0.100@ C A B ⊕ 0.100@ C A B dooolooo R0.115 TYP. Æ. 3.500 DETAIL Z 3.500±0.100 -PIN 1 CORNER EXPOSED PAD AREA AOB8_ME

Figure 46: 32-lead, ultra thin, fine pitch quad flat no-lead package (5 x 5)

- 1. Drawing is not to scale.
- 2. All leads/pads should also be soldered to the PCB to improve the lead/pad solder joint life.
- **3.** There is an exposed die pad on the underside of the UFQFPN package. It is recommended to connect and solder this backside pad to PCB ground.
- 4. Dimensions are in millimeters.

Table 54: 32-lead, ultra thin, fine pitch quad flat no-lead package mechanical data

Dim.	mm i			inches ⁽¹⁾		
	Min	Тур	Max	Min	Тур	Max
А	0.500	0.550	0.600	0.0197	0.0217	0.0236
A1	0	0.020	0.050		0.0008	0.0020
A3		0.200			0.0079	

Dim.	mm			inches ⁽¹⁾		
	Min	Тур	Max	Min	Тур	Max
b	0.180	0.250	0.300	0.0071	0.0098	0.0118
D	4.850	5.000	5.150	0.1909	0.1969	0.2028
D2	3.200	3.450	3.700	0.1260		0.1457
E	4.850	5.000	5.150	0.1909	0.1969	0.2028
E2	3.200	3.450	3.700	0.1260	0.1358	0.1457
е		0.500			0.0197	
L	0.300	0.400	0.500	0.0118	0.0157	0.0197
ddd			0.080			0.0031

 $^{^{(1)}}$ Values in inches are converted from mm and rounded to 4 decimal digits.

11.3 UFQFPN recommended footprint

0.5mm | 0.8mm | [0.032"] | 0.5mm | 0.9mm | 0.035"] | 0.3mm | [0.012"] | 4mm | [0.157"] | ai15319

Figure 47: Recommended footprint for on-board emulation

1. Drawing is not to scale

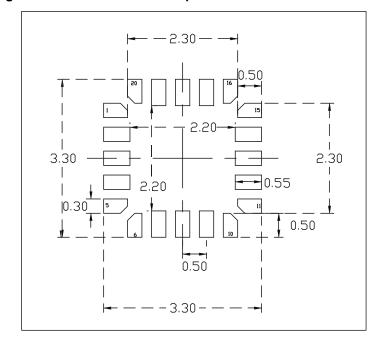


Figure 48: Recommended footprint without on-board emulation

- 1. Drawing is not to scale
- 2. Dimensions are in millimeters

11.4 SDIP32 package mechanical data

Figure 49: 32-lead shrink plastic DIP (400 ml) package

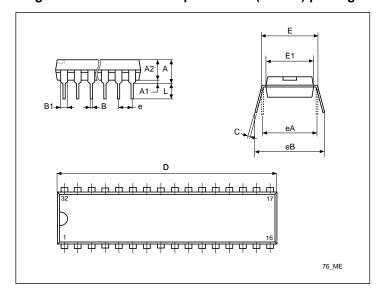


Table 55: 32-lead shrink plastic DIP (400 ml) package mechanical data

Dim.	mm			inches ⁽¹⁾		
	Min	Тур	Max	Min	Тур	Max
А	3.556	3.759	5.080	0.1400	0.1480	0.2000
A1	0.508			0.0200		
A2	3.048	3.556	4.572	0.1200	0.1400	0.1800
В	0.356	0.457	0.584	0.0140	0.0180	0.0230
B1	0.762	1.016	1.397	0.0300	0.0400	0.0550
С	0.203	0.254	0.356	0.0079	0.0100	0.0140
D	27.430	27.940	28.450	1.0799	1.1000	1.1201
E	9.906	10.410	11.050	0.3900	0.4098	0.4350
E1	7.620	8.890	9.398	0.3000	0.3500	0.3700
е		1.778			0.0700	
eA		10.160			0.4000	
еВ			12.700			0.5000
L	2.540	3.048	3.810	0.1000	0.1200	0.1500

 $^{^{(1)}}$ Values in inches are converted from mm and rounded to 4 decimal digits

11.5 20-pin TSSOP package mechanical data

D C C SAME

Figure 50: 20-pin, 4.40 mm body, 0.65 mm pitch

Table 56: 20-pin, 4.40 mm body, 0.65 mm pitch mechanical data

Dim.	mm			inches ⁽¹⁾		
	Min	Тур	Мах	Min	Тур	Max
А			1.200			0.0472
A1	0.050		0.150	0.0020		0.0059
A2	0.800	1.000	1.050	0.0315	0.0394	0.0413
b	0.190		0.300	0.0075		0.0118
С	0.090		0.200	0.0035		0.0079
D	6.400	6.500	6.600	0.2520	0.2559	0.2598
E	6.200	6.400	6.600	0.2441	0.2520	0.2598
E1	4.300	4.400	4.500	0.1693	0.1732	0.1772
е		0.650			0.0256	
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1		1.000			0.0394	

Dim.	mm			inches ⁽¹⁾		
	Min	Тур	Max	Min	Тур	Max
k	0.0°		8.0°	0.0°		8.0°
aaa			0.100			0.0039

 $^{^{\}left(1\right) }$ Values in inches are converted from mm and rounded to 4 decimal digits

11.6 20-pin SO package mechanical data

Figure 51: 20-lead, plastic small outline (300 mils) package

Table 57: 20-lead, plastic small outline (300 mils) mechanical data

Dim.	mm			inches ⁽¹⁾		
	Min	Тур	Max	Min	Тур	Max
А	2.350		2.650	0.0925		0.1043
A1	0.100		0.300	0.0039		0.0118
В	0.330		0.510	0.013		0.0201
С	0.230		0.320	0.0091		0.0126
D	12.600		13.000	0.4961		0.5118
E	7.400		7.600	0.2913		0.2992
е		1.270			0.0500	

Dim.	mm			inches ⁽¹⁾		
	Min	Тур	Max	Min	Тур	Max
Н	10.000		10.650	0.3937		0.4193
h	0.250		0.750	0.0098		0.0295
L	0.400		1.270	0.0157		0.0500
k	0.0°		8.0°	0.0°		8.0°
ddd			0.100			0.0039

⁽¹⁾ Values in inches are converted from mm and rounded to 4 decimal digits

12 Thermal characteristics

The maximum chip junction temperature ($T_{J max}$) must never exceed the values given in *Operating conditions*.

The maximum chip-junction temperature, T_{Jmax} , in degrees Celsius, may be calculated using the following equation:

$$T_{Jmax} = T_{Amax} + (P_{Dmax} \times \Theta_{JA})$$

Where

- T_{Amax} is the maximum ambient temperature in °C
- Θ_{JA} is the package junction-to-ambient thermal resistance in °C/W
- P_{Dmax} is the sum of P_{INTmax} and P_{I/Omax} (PDmax = P_{INTmax} + P_{I/Omax})
- P_{INTmax} is the product of I_{DD} and V_{DD}, expressed in Watts. This is the maximum chip internal power.
- $\bullet \;\; \mathsf{P}_{\mathsf{I/Omax}}$ represents the maximum power dissipation on output pins

Where

 $P_{I/Omax} = \Sigma \left(V_{OL} * I_{OL} \right) + \Sigma ((V_{DD} - V_{OH}) * I_{OH}), \text{ taking into account the actual } V_{OL} / I_{OL \text{ and }} V_{OH} / I_{OH} \text{ of the } I/Os \text{ at low and high level in the application.}$

Symbol	Parameter ⁽¹⁾	Value	Unit
Θ_{JA}	Thermal resistance junction-ambient TSSOP20 - 4 x 4 mm	110	°C/W
Θ_{JA}	Thermal resistance junction-ambient SO20W (300 mils)	20	°C/W
Θ_{JA}	Thermal resistance junction-ambient LQFP32 - 7 x 7 mm	60	°C/W
Θ_{JA}	Thermal resistance junction-ambient UFQFPN32 - 5 x 5 mm	38	°C/W
Θ_{JA}	Thermal resistance junction-ambient SDIP32 - 400 mils	60	°C/W

Table 58: Thermal characteristics

⁽¹⁾ Thermal resistances are based on JEDEC JESD51-2 with 4-layer PCB in a natural convection environment.

12.1 Reference document

JESD51-2 integrated circuits thermal test method environment conditions - natural convection (still air). Available from www.jedec.org.

12.2 Selecting the product temperature range

When ordering the microcontroller, the temperature range is specified in the order code.

The following example shows how to calculate the temperature range needed for a given application.

Assuming the following application conditions:

- Maximum ambient temperature T_{Amax} = 75 °C (measured according to JESD51-2)
- I_{DDmax} = 8 mA, V_{DD} = 5 V
- Maximum 20 I/Os used at the same time in output at low level with

$$I_{OL}$$
 = 8 mA, V_{OL} = 0.4 V

 $P_{INTmax} = 8 \text{ mA } x 5 \text{ V} = 400 \text{ mW}$ Amax

P_{Dmax} = 400 _{mW +} 64 mW

Thus: P_{Dmax} = 464 mW

 T_{Jmax} for LQFP32 can be calculated as follows, using the thermal resistance Θ_{JA} :

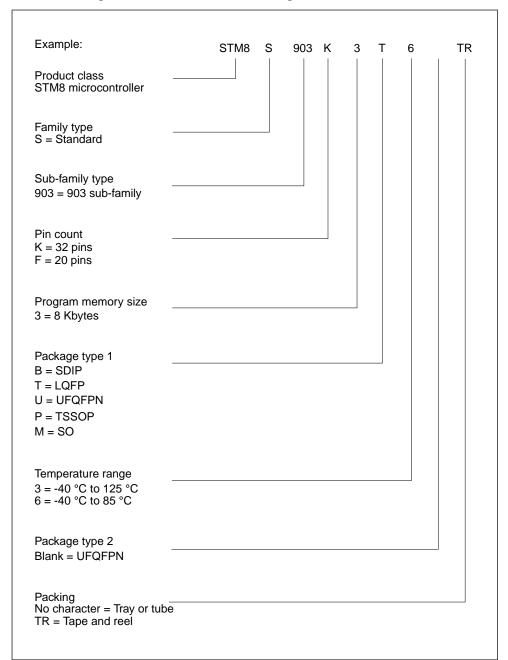
$$T_{\text{.lmax}} = 75 \,^{\circ}\text{C} + (60 \,^{\circ}\text{C/W} \,\text{x} \, 464 \,\text{mW}) = 75 \,^{\circ}\text{C} + 27.8 \,^{\circ}\text{C} = 102.8 \,^{\circ}\text{C}$$

This is within the range of the suffix 6 version parts (-40 < $T_{.1}$ < 105 °C).

In this case, parts must be ordered at least with the temperature range suffix 6.

13 Ordering information

Figure 52: STM8S903K3 ordering information scheme



- **1.** The package pitch digit is used only when several dimensions are available for the same package.
- 2. A dedicated ordering information scheme will be released if, in the future, memory programming service (FastROM) is required. The letter "P" will be added after STM8S. Three unique letters identifying the customer application code will also be visible in the codification. Example: STM8SP903K3MACTR.



For a list of available options (e.g. memory size, package) and orderable part numbers or for further information on any aspect of this device, please go to www.st.com or contact the ST Sales Office nearest to you.

13.1 STM8S903K3 FASTROM microcontroller option list

(last update: April 2010)

Customer	
Address	
Contact	
Phone no.	
Reference FASTROM code	FASTROM code name is assigned by STMicroelectronics

Preferable format for programing code is .Hex (.s19 is accepted)

If data EEPROM programing is required, a seperate file must be sent with the requested data.

Important: See the option byte section in the datasheet for authorized option byte combinations and a detailed explanation. Do not use more than one remapping option in the same port. It is forbidden to enable both AFR1 and AFR0.

Device type/memory size/package

FASTROM device	8 Kbyte
LQFP32	[]STM8S903K3
TSSOP20	[]STM8S903F3
SO20	[]STM8S903F3
UFQFPN32	[]STM8S903K3

Conditioning (check only one option)

[] Tape & reel or [] Tray

Special marking (check only one option)

[] No [] Yes

Authorized characters are letters, digits, '.', '-', '/' and spaces only. Maximum character counts are:

LQFP32: 2 lines of 7 characters max: "_____" and "____"

TSSOP20: 1 line of 10 characters max: "_____" and "____"

SO20: 1 line of 13 characters max: "_____" and "____"

UFQFPN32: 1 line of 7 characters max: "_____" and "____"

Three characters are reserved for code identification.

Temperature range

[] -40 $^{\circ}$ C to +85 $^{\circ}$ C or [] -40 $^{\circ}$ C to +125 $^{\circ}$ C

Padding value for unused program memory (check only one option)

[]0xFF	Fixed value
[]0x83	TRAP instruction opcode
[]0x75	Illegal opcode (causes a reset when executed)

OPT0 memory readout protection (check only one option)

[] Disable or [] Enable

OPT1 user boot code area (UBC)

0x(__) fill in the hexadecimal value, refering to the datasheet and the binary format below.

UBC, bit0	[] 0: Reset [] 1: Set
UBC bit1	[] 0: Reset [] 1: Set
UBC bit2	[] 0: Reset [] 1: Set
UBC bit3	[] 0: Reset [] 1: Set
UBC bit4	[] 0: Reset [] 1: Set
UBC bit5	[] 0: Reset [] 1: Set
UBC bit6	[] 0: Reset [] 1: Set
UBC bit7	[] 0: Reset [] 1: Set

OPT2 alternate function remapping

Do not use more than one remapping option in the same port.

AEDO AEDA	
AFR0, AFR1 (check only one option)	[] 00: Remapping options inactive. Default alternate functions used. Refer to pinout description.
	[] 10: Port PC5 alternate function = TIM5_CH1, port PC6 alternate function = TIM1_CH1, and port PC7 alternate function = TIM1_CH2.
	[] 01: Port PA3 alternate function = SPI_NSS and port PD2 alternate function = TIM5_CH3.
	[] 11: Port PD2 alternate function = TIM5_CH3, port PC5 alternate function = TIM5_CH1, port PC6 alternate function = TIM1_CH1, port PC7 alternate function = TIM1_CH2, port PC2 alternate function = TIM1_CH3N, port PC1 alternate function = TIM1_CH2N, port PE5 alternate function = TIM1_CH1N, port PA3 alternate function = UART1_TX, and port PF4 alternate function = UART1_RX.
AFR2	[] 0: Remapping option inactive. Default alternate
(check only one option)	functions used. Refer to pinout description. [] 1: Port C4 alternate function = AIN2, port D2
	alternate function = AIN3, port D4 alternate function = UART1_CK.
AFR3	[] 0: Remapping option inactive. Default alternate
(check only one option)	functions used. Refer to pinout description. [] 1: Port C3 alternate function = TLI.
AFR4 (check only one option)	[] 0: Remapping option inactive. Default alternate functions used. Refer to pinout description.
	[] 1: Port B4 alternate function = ADC_ETR, port P5 alternate function = TIM1_BKIN.
AFR5	[] 0: Remapping option inactive. Default alternate
(check only one option)	functions used. Refer to pinout description. [] 1: Port D0 alternate function = CLK_CCO.
AFR6	[] 0: Remapping option inactive. Default alternate
(check only one option)	functions used. Refer to pinout description.
	[] 1: Port D7 alternate function = TIM1_CH4.
AFR7 (check only one option)	[] 0: Remapping option inactive. Default alternate functions used. Refer to pinout description.
(Greek only one option)	[] 1: Port C3 alternate function = TIM1_CH1N, port C4 alternate function = TIM1_CH2N.

OPT3 watchdog

WWDG_HALT (check only one option)	[] 0: No reset generated on halt if WWDG active
WWDG_HW (check only one option)	[] 0: WWDG activated by software [] 1: WWDG activated by hardware
IWDG_HW (check only one option)	[] 0: IWDG activated by software [] 1: IWDG activated by hardware
LSI_EN (check only one option)	[] 0: LSI clock is not available as CPU clock source [] 1: LSI clock is available as CPU clock source
HSITRIM (check only one option)	[] 0: 3-bit trimming supported in CLK_HSITRIMR register [] 1: 4-bit trimming supported in CLK_HSITRIMR register

OPT4 wakeup

PRSC (check only one option)	[] for 16 MHz to 128 kHz prescaler [] for 8 MHz to 128 kHz prescaler [] for 4 MHz to 128 kHz prescaler
CKAWUSEL (check only one option)	[] LSI clock source selected for AWU [] HSE clock with prescaler selected as clock source for for AWU
EXTCLK (check only one option)	[] External crystal connected to OSCIN/OSCOUT

OPT5 crystal oscillator stabilization HSECNT (check only one option)

ſ	1	2048	HSE	cyc	les
---	---	------	-----	-----	-----

- [] 128 HSE cycles
- [] 8 HSE cycles
- [] 0.5 HSE cycles

OPT6 is reserved

Comments:	
Supply operating range in the application:	

Notes:	
Notes:	

14 STM8 development tools

Development tools for the STM8 microcontrollers include the full-featured STice emulation system supported by a complete software tool package including C compiler, assembler and integrated development environment with high-level language debugger. In addition, the STM8 is to be supported by a complete range of tools including starter kits, evaluation boards and a low-cost in-circuit debugger/programmer.

14.1 Emulation and in-circuit debugging tools

The STice emulation system offers a complete range of emulation and in-circuit debugging features on a platform that is designed for versatility and cost-effectiveness. In addition, STM8 application development is supported by a low-cost in-circuit debugger/programmer.

The STice is the fourth generation of full featured emulators from STMicroelectronics. It offers new advanced debugging capabilities including profiling and coverage to help detect and eliminate bottlenecks in application execution and dead code when fine tuning an application.

In addition, STice offers in-circuit debugging and programming of STM8 microcontrollers via the STM8 single wire interface module (SWIM), which allows non-intrusive debugging of an application while it runs on the target microcontroller.

For improved cost effectiveness, STice is based on a modular design that allows you to order exactly what you need to meet your development requirements and to adapt your emulation system to support existing and future ST microcontrollers.

STice key features

- Occurrence and time profiling and code coverage (new features)
- Advanced breakpoints with up to 4 levels of conditions
- Data breakpoints
- Program and data trace recording up to 128 KB records
- Read/write on the fly of memory during emulation
- In-circuit debugging/programming via SWIM protocol
- 8-bit probe analyzer
- 1 input and 2 output triggers
- Power supply follower managing application voltages between 1.62 to 5.5 V
- Modularity that allows you to specify the components you need to meet your development requirements and adapt to future requirements
- Supported by free software tools that include integrated development environment (IDE), programming software interface and assembler for STM8.

14.2 Software tools

STM8 development tools are supported by a complete, free software package from STMicroelectronics that includes ST Visual Develop (STVD) IDE and the ST Visual Programmer (STVP) software interface. STVD provides seamless integration of the Cosmic and Raisonance C compilers for STM8, which are available in a free version that outputs up to 16 Kbytes of code.



14.2.1 STM8 toolset

STM8 toolset with STVD integrated development environment and STVP programming software is available for free download at www.st.com/mcu. This package includes:

ST Visual Develop - Full-featured integrated development environment from ST, featuring

- Seamless integration of C and ASM toolsets
- Full-featured debugger
- Project management
- Syntax highlighting editor
- Integrated programming interface
- Support of advanced emulation features for STice such as code profiling and coverage

ST Visual Programmer (STVP) – Easy-to-use, unlimited graphical interface allowing read, write and verify of your STM8 microcontroller's Flash program memory, data EEPROM and option bytes. STVP also offers project mode for saving programming configurations and automating programming sequences.

14.2.2 C and assembly toolchains

Control of C and assembly toolchains is seamlessly integrated into the STVD integrated development environment, making it possible to configure and control the building of your application directly from an easy-to-use graphical interface.

Available toolchains include:

- Cosmic C compiler for STM8 Available in a free version that outputs up to 16 Kbytes of code. For more information, see www.cosmic-software.com.
- Raisonance C compiler for STM8 Available in a free version that outputs up to 16 Kbytes of code. For more information, see www.raisonance.com.
- **STM8 assembler linker** Free assembly toolchain included in the STVD toolset, which allows you to assemble and link your application source code.

14.3 Programming tools

During the development cycle, STice provides in-circuit programming of the STM8 Flash microcontroller on your application board via the SWIM protocol. Additional tools are to include a low-cost in-circuit programmer as well as ST socket boards, which provide dedicated programming platforms with sockets for programming your STM8.

For production environments, programmers will include a complete range of gang and automated programming solutions from third-party tool developers already supplying programmers for the STM8 family.

15 Revision history

Table 59: Document revision history

Date	Revision	Changes
30-Apr-2009	1	Initial revision
03-Jun-2009	2	Added bullet point concerning unique identifier to <i>Features</i> section on cover page.
		Highlighted internal reference voltage in <i>Analog-to-digital</i> converter (ADC1) section.
		Updated wpu and PP status of PB5/12C_SDA[TIM1_BKIN] and PB4/12C_SCL[ADC_ETR] pins in <i>Pin description</i> .
		Updated Figure 6: Memory map.
		Added <i>Unique ID</i> section.
		Added TBD values to Table 44: SPI characteristics.
		Added max values to Table 47: ADC accuracy with RAIN < 10 $k\Omega$, VDD= 5 V and Table 48: ADC accuracy with RAIN < 10 $k\Omega$ RAIN, VDD = 3.3 V.
22-Apr-2010	3	Added SO20W, TSSOP20, SDIP32, and UFQFPN32 packages.
		Added STM8S903F3 part number.
		Updated datasheet status to full datasheet.
		Updated definition of alternate function remapping option in <i>Table 4: Legend/abbreviations for pinout tables</i> .
		Updated Px_IDR reset value in <i>Table 6: I/O port hardware register map</i> table.
		Removed ESR low limit and update high limit for CEXT conditions in <i>Table 20: General operating conditions</i> .
		Operating conditions: updated VCAP and ESR low limit, added ESL parameter, as well as P _D in <i>Table 20: General operating conditions</i> .
		Functional EMS (electromagnetic susceptibility): changed ESD to FESD (functional ESD); added name of AN1709; replaced IEC 1000 with IEC 61000.
		Designing hardened software to avoid noise problems replaced IEC 1000 with IEC 61000, added title of AN1015, and added footnote to Table 49: EMS data.
		Electromagnetic interference (EMI) replaced J 1752/3 with IEC 61967-2 and updated data of Table 50: EMI data.
		Removed note 3 related to Accuracy of HSI oscillator.

Date	Revision	Changes	
		Updated OJA in <i>Table 14: STM8S903K3 alternate function</i> remapping bits [1:0] for 32-pin packages. Changed OJA to 60°C/W in <i>Selecting the product temperature range</i> section.	
		Ordering information: replaced package pitch digit by VFQFPN/UFQFPN package, and added footnote regarding possible future release of a dedicated ordering information scheme. Added SO20W, TSSOP20, SDIP32, and UFQFPN32.	
		Added STM8S903K3 FASTROM microcontroller option list.	
30-Apr-2010	4	Modified P_D at T_A = 85 °C for SO20W in <i>Table 20: General operating conditions</i> .	
08-Sep-2010	5	Removed VFQFPN32 package.	
		Updated "reset state" of Table 4: Legend/abbreviations for pinout tables in Pinout and pin description.	
		Table 5: TSSOP20/SO20/UFQFPN32/LQFP32/SDIP32 pin description: updated pins 13/25/20, 14/26/21, 19/32/27, 1/2/29, 2/3/30, and 3/4/31; added footnote to PD1/SWIM pin.	
		General hardware register map: standardized all reset state values; updated the reset state values of RST_SR, CLK_SWCR, CLK_HSITRIMR, CLK_SWIMCCR, IWDG_KR, and ADC_DRx registers in the "General hardware register map" table.	
		Changed title of <i>Table 12: STM8S903K3 alternate function remapping bits</i> [7:2] for 32-pin packages.	
		Added Table 13: STM8S903F3 alternate function remapping bits [7:2] for 20-pin packages.	
		Changed title of <i>Table 14: STM8S903K3 alternate function remapping bits</i> [1:0] for 32-pin packages.	
		Added Table 15: STM8S903F3 alternate function remapping bits [1:0] for 20-pin packages.	
		Reset pin characteristics: replaced 0.01 μF with 0.1 μF in the "Recommended reset pin protection" diagram.	
		Added #unique_56/title_4B4D811961B64279B556EDC351811802	
		Updated footnote 1 in Table 47: ADC accuracy with RAIN < 10 $k\Omega$, VDD= 5 V and Table 48: ADC accuracy with RAIN < 10 $k\Omega$ RAIN, VDD = 3.3 V .	
		#unique_75/CD14: updated existing footnote and added three additional footnotes.	

Date	Revision	Changes
		Updated "special marking" and "OPT2 alternate function remapping" sections in the STM8S903K3 FASTROM microcontroller option list.

Please Read Carefully

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at anytime, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein

UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

UNLESS EXPRESSLY APPROVED IN WRITING BY AN AUTHORIZED ST REPRESENTATIVE, ST PRODUCTS ARE NOT RECOMMENDED, AUTHORIZED OR WARRANTED FOR USE IN MILITARY, AIR CRAFT, SPACE, LIFE SAVING, OR LIFE SUSTAINING APPLICATIONS, NOR IN PRODUCTS OR SYSTEMS WHERE FAILURE OR MALFUNCTION MAY RESULT IN PERSONAL INJURY, DEATH, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE. ST PRODUCTS WHICH ARE NOT SPECIFIED AS "AUTOMOTIVEGRADE" MAY ONLY BE USED IN AUTOMOTIVE APPLICATIONS AT USER'S OWN RISK.

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately voidany warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

© 2010 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco - Philippines - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

www.st.com

477